

8-BIT SINGLE-CHIP MICROCONTROLLER

DESCRIPTION

μ PD780306Y and 780308Y are products in the μ PD780308Y subseries within the 78K/0 series, which incorporates LCD controller/driver, 8-bit resolution A/D converter, timer, serial interface, interrupt functions and many other peripheral hardwares.

A one-time PROM product capable of operating in the same power supply voltage range as of the mask ROM product, EPROM product, μ PD78P0308Y, and other development tools are available.

For the details of functional description, refer to the following user's manual.

μ PD780308, 780308Y Subseries User's Manual : U11377E
78K/0 Series User's Manual (Instruction) : U12326E

FEATURES

- Large on-chip ROM & RAM

Item Product Name	Program Memory (ROM)	Data Memory		
		High-Speed RAM	Expansion RAM	LCD Display RAM
μ PD780306Y	48K bytes	1024 bytes	1024 bytes	40 × 4 bits
μ PD780308Y	60K bytes			

- Minimum instruction execution time can be varied from high speed (0.4 μ s) to ultra-low speed (122 μ s)
- I/O ports: 57 (including segment signal output dual-function pins)
- LCD controller/driver
Supply voltage : $V_{DD} = 2.0$ to 5.5 V (Operable in any mode)
- 8-bit resolution A/D converter : 8 channels
- Serial interface : 3 channels
- Timer: 5 channels
- Supply voltage : $V_{DD} = 2.0$ to 5.5 V

APPLICATION FIELD

Celullar phones, compact disk players, cameras, meters, etc.

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Not all devices/types available in every country. Please check with local NEC representative for availability and additional information.

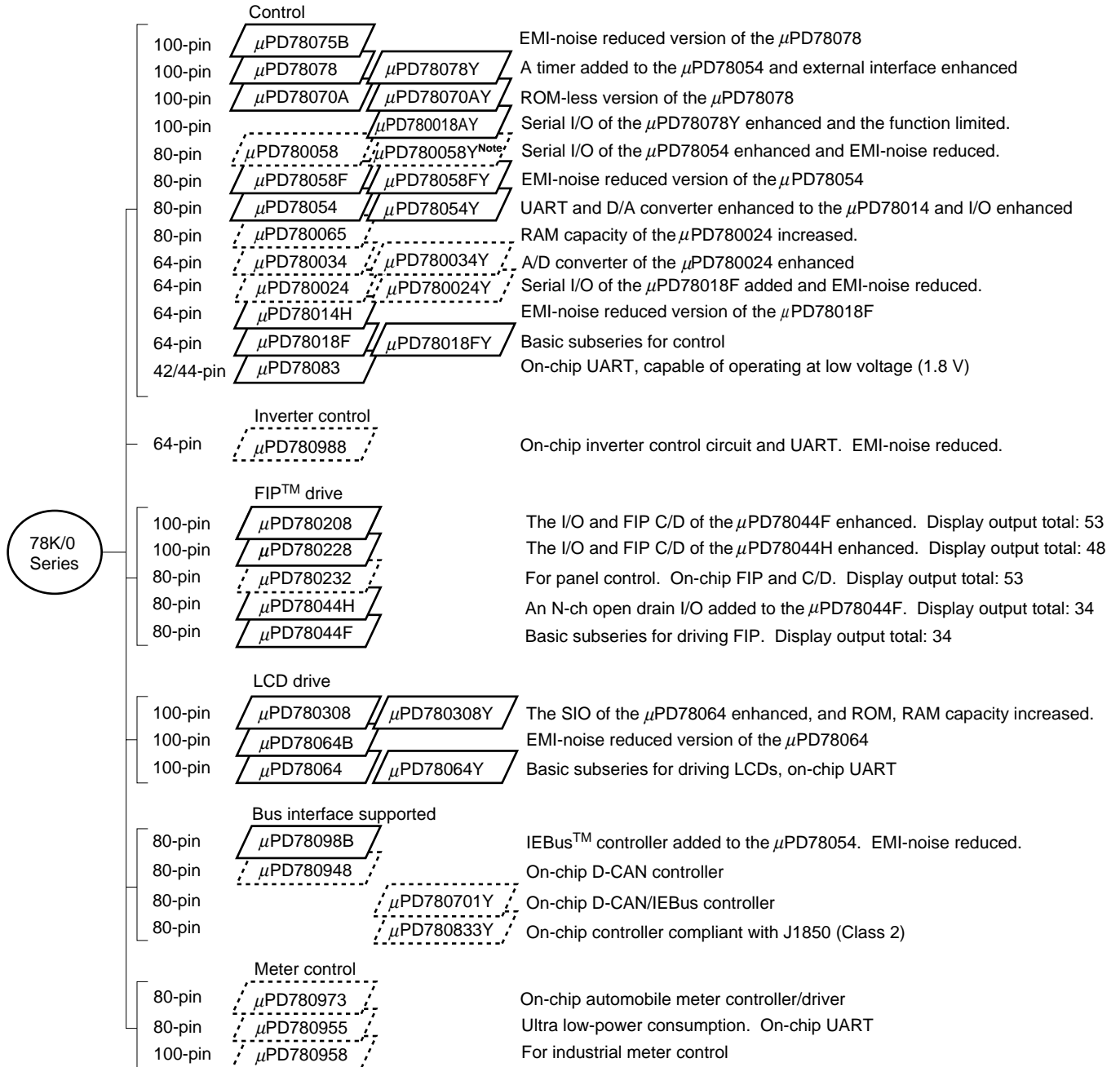
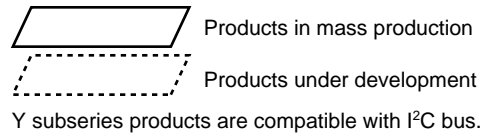
ORDERING INFORMATION

	Part Number	Package
★	μ PD780306YGC-xxx-8EU	100-pin plastic LQFP (Fine pitch) (14 × 14 mm)
	μ PD780306YGF-xxx-3BA	100-pin plastic QFP (14 × 20 mm)
★	μ PD780308YGC-xxx-8EU	100-pin plastic LQFP (Fine pitch) (14 × 14 mm)
	μ PD780308YGF-xxx-3BA	100-pin plastic QFP (14 × 20 mm)

Remark xxx indicates ROM code suffix.

★ 78K/0 SERIES DEVELOPMENT

The following shows the products organized according to usage. The names in the parallelograms are subseries names.



Note Under planning

The following lists the main functional differences between Y subseries products.

Function		ROM Capacity	Serial Interface	I/O	V _{DD} MIN Value
Subseries Name					
Control	μPD78078Y	48 K to 60 K	3-wire/2-wire/I ² C : 1 ch With automatic transmit/receive function, 3-wire : 1 ch	88	1.8 V
	μPD78070AY	–	3-wire/UART : 1 ch	61	2.7 V
	μPD780018AY	48 K to 60 K	With automatic transmit/receive function, 3-wire : 1 ch Time division 3-wire : 1 ch I ² C bus (multi master supported) : 1 ch	88	
	μPD780058BY	24 K to 60 K	3-wire/2-wire/I ² C : 1 ch With automatic transmit/receive function, 3-wire : 1 ch 3-wire/Time division UART : 1 ch	68	1.8 V
	μPD78058FY	48 K to 60 K	3-wire/2-wire/I ² C : 1 ch With automatic transmit/receive function, 3-wire : 1 ch	69	2.7 V
	μPD78054Y	16 K to 60 K	3-wire/UART : 1 ch		2.0 V
	μPD780034Y	8 K to 32 K	UART : 1 ch 3-wire : 1 ch	51	1.8 V
	μPD780024Y		I ² C bus (multi master supported) : 1 ch		
	μPD78018FY	8 K to 60 K	3-wire/2-wire/I ² C : 1 ch With automatic transmit/receive function, 3-wire : 1 ch	53	
LCD drive	μPD780308Y	48 K to 60 K	3-wire/2-wire/I ² C : 1 ch 3-wire/Time division UART : 1 ch 3-wire : 1 ch	57	2.0 V
	μPD78064Y	16 K to 32 K	3-wire/2-wire/I ² C : 1 ch 3-wire/UART : 1 ch		

Remark The functions other than the serial interface are the same as those of subseries products without the suffix Y.

OVERVIEW OF FUNCTION

Product Name		μPD780306Y	μPD780308Y
Internal memory	ROM	48K bytes	60K bytes
	High-speed RAM	1024 bytes	
	Expansion RAM	1024 bytes	
	LCD display RAM	40 × 4 bits	
General registers		8 bits × 32 registers (8 bits × 8 registers × 4 banks)	
Minimum instruction execution time		On-chip minimum instruction execution time cycle modification function	
	When main system clock selected	0.4 μs/0.8 μs/1.6 μs/3.2 μs/6.4 μs/12.8 μs (at 5.0 MHz operation)	
	When subsystem clock selected	122 μs (at 32.768 kHz operation)	
Instruction set		<ul style="list-style-type: none"> • 16-bit operation • Multiplication/division (8 bits × 8 bits, 16 bits ÷ 8 bits) • Bit manipulation (set, reset, test, boolean operation) • BCD correction, etc. 	
I/O ports (including segment signal output pins)		Total : 57 <ul style="list-style-type: none"> • CMOS input : 2 • CMOS I/O : 55 	
A/D converter		• 8-bit resolution × 8 channels	
LCD controller/driver		<ul style="list-style-type: none"> • Segment signal output : Maximum 40 • Common signal output : Maximum 4 • Bias : 1/2 or 1/3 switchable 	
Serial interface		<ul style="list-style-type: none"> • 3-wire serial I/O/I²C bus/2-wire serial I/O mode selectable : 1 channel • 3-wire serial I/O/UART mode selectable : 1 channel • 3-wire serial I/O mode : 1 channel 	
Timer		<ul style="list-style-type: none"> • 16-bit timer/event counter : 1 channel • 8-bit timer/event counter : 2 channels • Watch timer : 1 channel • Watchdog timer : 1 channel 	
Timer output		3 (14-bit PWM output capability : 1)	
Clock output		19.5 kHz, 39.1 kHz, 78.1 kHz, 156 kHz, 313 kHz, 625 kHz, 1.25 MHz, 2.5 MHz, 5.0 MHz (at main system clock: 5.0 MHz operation) 32.768 kHz (at subsystem clock: 32.768 kHz operation)	
Buzzer output		1.2 kHz, 2.4 kHz, 4.9 kHz, 9.8 kHz (at main system clock 5.0 MHz operation)	
Vectored interrupt sources	Maskable	Internal: 13, external: 6	
	Non-maskable	Internal: 1	
	Software	1	
Test input		Internal: 1, external: 1	
Supply voltage		V _{DD} = 2.0 to 5.5 V	
Package		<ul style="list-style-type: none"> • 100-pin plastic LQFP (Fine pitch) (14 × 14 mm) • 100-pin plastic QFP (14 × 20 mm) 	

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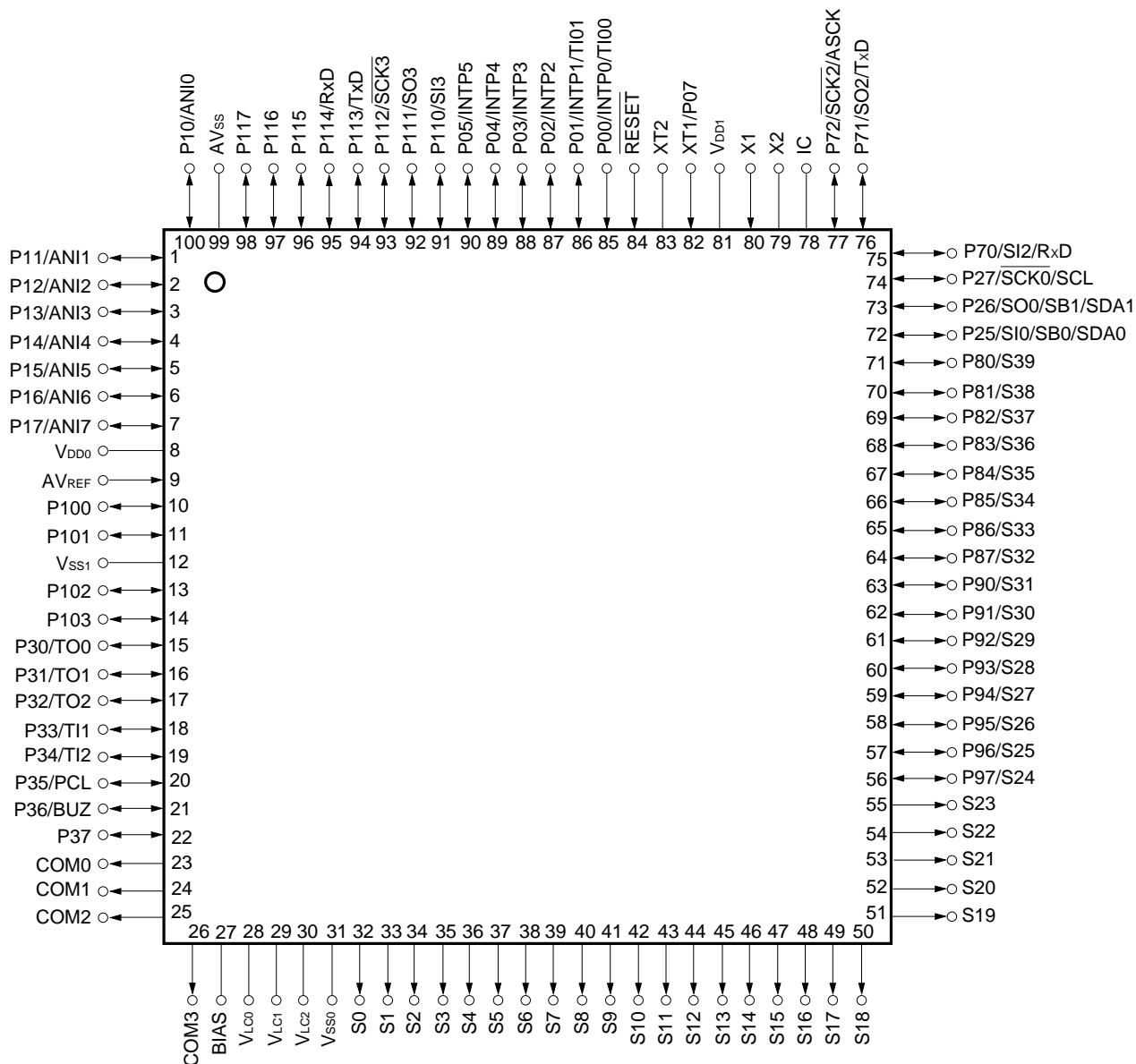
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1. PIN CONFIGURATION (TOP VIEW)

• 100-pin plastic LQFP (Fine pitch) (14 × 14 mm)

μPD780306YGC-xxx-8EU, 780308YGC-xxx-8EU

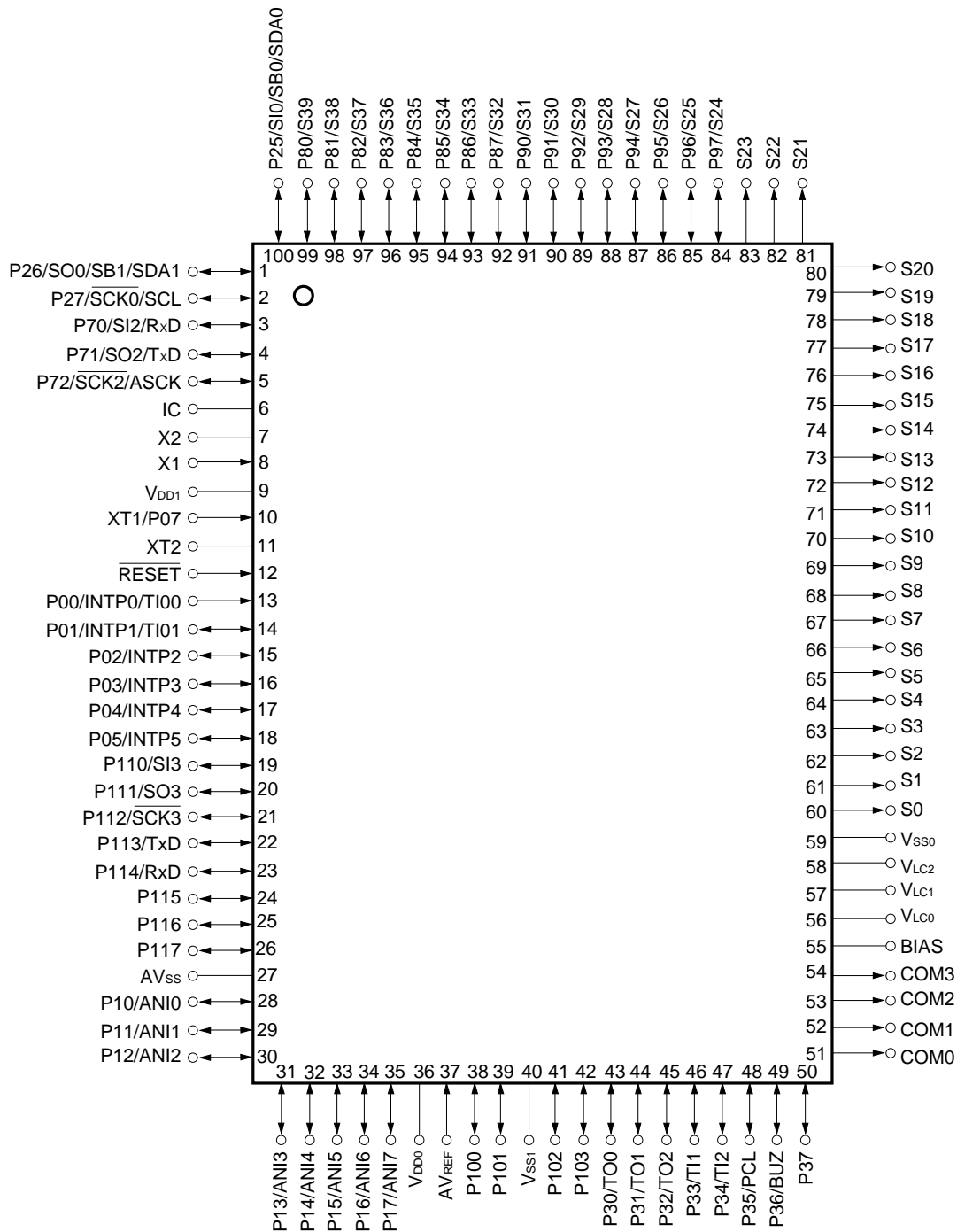


- Cautions 1.** Connect directly the IC (Internally Connected) pin to V_{SS0} or V_{SS1}.
2. Connect the AV_{SS} pin to V_{SS0}.

Remark When using in applications where noise from inside the microcontroller has to be reduced, it is recommended that countermeasures against the noise are taken, such as supplying power separately to V_{DD0} and V_{DD1}, and connecting V_{DD0} and V_{DD1} to ground lines separately.

• 100-pin plastic QFP (14 × 20 mm)

μPD780306YGF-xxx-3BA, 780308YGF-xxx-3BA

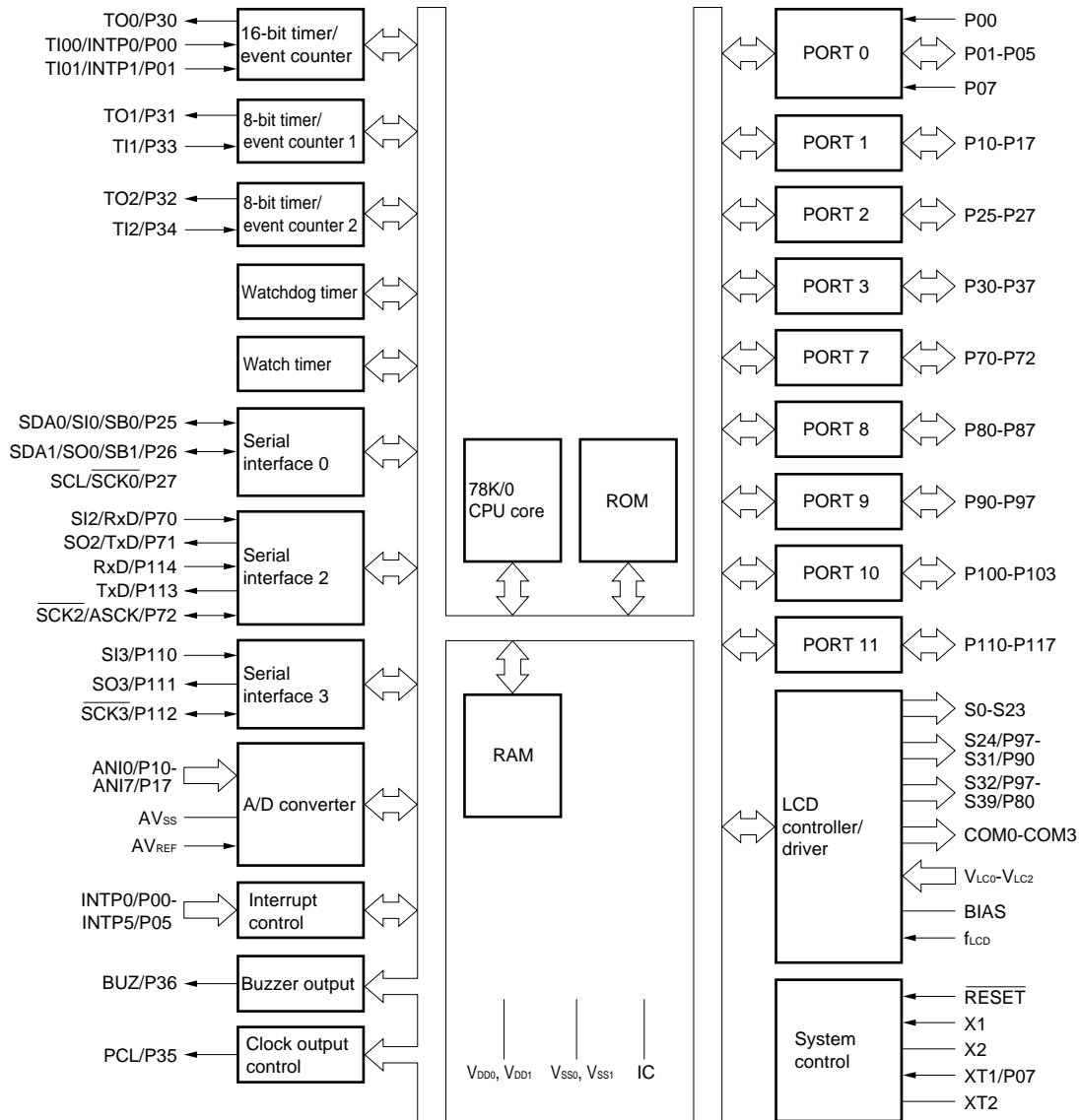


- Cautions**
1. Connect directly the IC (Internally Connected) pin to V_{SS0} or V_{SS1}.
 2. Connect the AV_{SS} pin to V_{SS0}.

Remark When using in applications where noise from inside the microcontroller has to be reduced, it is recommended that countermeasures against the noise are taken, such as supplying power separately to V_{DD0} and V_{DD1}, and connecting V_{DD0} and V_{DD1} to ground lines separately.

ANI0 to ANI7	: Analog Input	PCL	: Programmable Clock
ASCK	: Asynchronous Serial Clock	$\overline{\text{RESET}}$: Reset
AVREF	: Analog Reference Voltage	RxD	: Receive Data
AVss	: Analog Ground	S0 to S39	: Segment Output
BIAS	: LCD Power Supply Bias Control	SB0, SB1	: Serial Bus
BUZ	: Buzzer Clock	$\overline{\text{SCK0}}, \overline{\text{SCK2}}, \overline{\text{SCK3}}$: Serial Clock
COM0 to COM3	: Common Output	SCL	: Serial Clock
IC	: Internally Connected	SDA0, SDA1	: Serial Data
INTP0 to INTP5	: Interrupt from Peripherals	SI0, SI2, SI3	: Serial Input
P00 to P05, P07	: Port0	SO0, SO2, SO3	: Serial Output
P10 to P17	: Port1	TI00, TI01, TI1, TI2	: Timer Input
P25 to P27	: Port2	TO0 to TO2	: Timer Output
P30 to P37	: Port3	TxD	: Transmit Data
P70 to P72	: Port7	VDD0, VDD1	: Power Supply
P80 to P87	: Port8	VLC0 to VLC2	: LCD Power Supply
P90 to P97	: Port9	VSS0, VSS1	: Ground
P100 to P103	: Port10	X1, X2	: Crystal (Main System Clock)
P110 to P117	: Port11	XT1, XT2	: Crystal (Subsystem Clock)

2. BLOCK DIAGRAM



Remark The internal ROM capacity varies depending on the product.

3. PIN FUNCTIONS

3.1 PORT PINS (1/2)

Pin Name	I/O	Function		On Reset	Dual-Function Pin
P00	Input	Port 0 7-bit I/O port.	Input only	Input	INTP0/TI00
P01	Input/ output		Input/output can be specified bit-wise. When used as an input port, internal pull-up resistor can be used by software.	Input	INTP1/TI01
P02					INTP2
P03					INTP3
P04					INTP4
P05					INTP5
P07 ^{Note1}	Input		Input only	Input	XT1
P10 to P17	Input/ output	Port 1 8-bit input/output port. Input/output can be specified bit-wise. When used as an input port, internal pull-up resistor can be used by software. ^{Note2}		Input	ANI0 to ANI7
P25	Input/ output	Port 2 3-bit input/output port. Input/output can be specified bit-wise. When used as an input port, internal pull-up resistor can be used by software.		Input	SI0/SB0/ SDA0
P26					SO0/SB1/ SDA1
P27					SCK0/SCL
P30	Input/ output	Port 3 8-bit input/output port. Input/output can be specified bit-wise. When used as an input port, internal pull-up resistor can be used by software.		Input	TO0
P31					TO1
P32					TO2
P33					TI1
P34					TI2
P35					PCL
P36					BUZ
P37					—
P70	Input/ output	Port 7 3-bit input/output port. Input/output can be specified bit-wise. When used as an input port, internal pull-up resistor can be used by software.		Input	SI2/RxD
P71					SO2/TxD
P72					SCK2/ ASCK

- Notes**
1. When using the P07/XT1 pins as an input port, set (1) bit 6 (FRC) of the processor clock control register (PCC) (the on-chip feedback resistor of the subsystem clock oscillator should not be used).
 2. When using the P10/ANI0 to P17/ANI7 pins as the A/D converter analog input, port 1 is set to input mode. However, internal pull-up resistor is not automatically used.

3.1 PORT PINS (2/2)

Pin Name	I/O	Function	On Reset	Dual-Function Pin
P80 to P87	Input/output	Port 8 8-bit input/output port Input/output can be specified bit-wise. When used as an input port, internal pull-up resistor can be used by software. Input/output port/segment signal output function can be specified in 2-bit unit by the LCD display control register (LCDC).	Input	S39 to S32
P90 to P97	Input/output	Port 9 8-bit input/output port Input/output can be specified bit-wise. When used as an input port, internal pull-up resistor can be used by software. Input/output port/segment signal output function can be specified in 2-bit unit by the LCD display control register (LCDC).	Input	S31 to S24
P100 to P103	Input/output	Port 10 4-bit input/output port Input/output can be specified bit-wise. When used as an input port, internal pull-up resistor can be used by software. LED direct drive capability.	Input	—
P110	Input/output	Port 11 8-bit input/output port Input/output can be specified bit-wise. When used as an input port, internal pull-up resistor can be used by software. Falling edge detection capability.	Input	SI3
P111				SO3
P112				SCK3
P113				TxD
P114				RxD
P115 to P117				—

3.2 OTHER PINS (1/2)

Pin Name	I/O	Function	On Reset	Dual-Function Pin
INTP0	Input	External interrupt request input by which the effective edge (rising edge, falling edge, or both rising edge and falling edge) can be specified.	Input	P00/TI00
INTP1				P01/TI01
INTP2				P02
INTP3				P03
INTP4				P04
INTP5				P05
SI0	Input	Serial interface serial data input.	Input	P25/SB0/SDA0
SI2				P70/RxD
SI3				P110
SO0	Output	Serial interface serial data output.	Input	P26/SB1/SDA1
SO2				P71/TxD
SO3				P111
SB0	Input/ output	Serial interface serial data input/output.	Input	P25/SI0/SDA0
SB1				P26/SO0/SDA1
SDA0				P25/SI0/SB0
SDA1				P26/SO0/SB1
$\overline{\text{SCK0}}$	Input/ output	Serial interface serial clock input/output.	Input	P27
$\overline{\text{SCK2}}$				P72/ASCK
$\overline{\text{SCK3}}$				P112
SCL				P27/ $\overline{\text{SCK0}}$
RxD	Input	Asynchronous serial interface serial data input.	Input	P70/SI2, P114
TxD	Output	Asynchronous serial interface serial data output.	Input	P71/SO2, P113
ASCK	Input	Asynchronous serial interface serial clock input.	Input	P72/ $\overline{\text{SCK2}}$
TI00	Input	External count clock input to 16-bit timer (TM0).	Input	P00/INTP0
TI01		Capture trigger signal input to capture register (CR00).		P01/INTP1
TI1		External count clock input to 8-bit timer (TM1).		P33
TI2		External count clock input to 8-bit timer (TM2).		P34
TO0	Output	16-bit timer output (shared with 14-bit PWM output).	Input	P30
TO1		8-bit timer output.		P31
TO2				P32
PCL	Output	Clock output (for main system clock, subsystem clock trimming).	Input	P35
BUZ	Output	Buzzer output.	Input	P36
S0 to S23	Output	LCD controller/driver segment signal output.	Output	—
S24 to S31			Input	P97 to P90
S32 to S39				P87 to P80
COM0 to COM3	Output	LCD controller/driver common signal output.	Output	—
VLC0 to VLC2	—	LCD drive voltage. Split resistors can be incorporated by mask option.	—	—
BIAS	—	LCD drive power supply.	—	—

3.2 OTHER PINS (2/2)

Pin Name	I/O	Function	On Reset	Dual-Function Pin
ANI0 to ANI7	Input	A/D converter analog input.	Input	P10 to P17
AV _{REF}	Input	Reference voltage input of A/D converter and D/A converter (shared with analog power supply).	—	—
AV _{SS}	—	Ground potential of A/D converter and D/A converter. Set the same potential as V _{SS0} .	—	—
RESET	Input	System reset input.	—	—
X1	Input	Main system clock oscillation crystal connection.	—	—
X2	—		—	—
XT1	Input	Subsystem clock oscillation crystal connection.	Input	P07
XT2	—		—	—
V _{DD0}	—	Positive power supply for port block.	—	—
V _{SS0}	—	Ground potential for port block.	—	—
V _{DD1}	—	Positive power supply (except port block).	—	—
V _{SS1}	—	Ground potential (except port and analog block).	—	—
IC	—	Internally connected. Connect directly to V _{SS0} or V _{SS1} pin.	—	—

3.3 PIN I/O CIRCUITS AND RECOMMENDED CONNECTION OF UNUSED PINS

The input/output circuit type of each pin and recommended connection of unused pins are shown in Table 3-1. For the input/output circuit configuration of each type, refer to **Figure 3-1**.

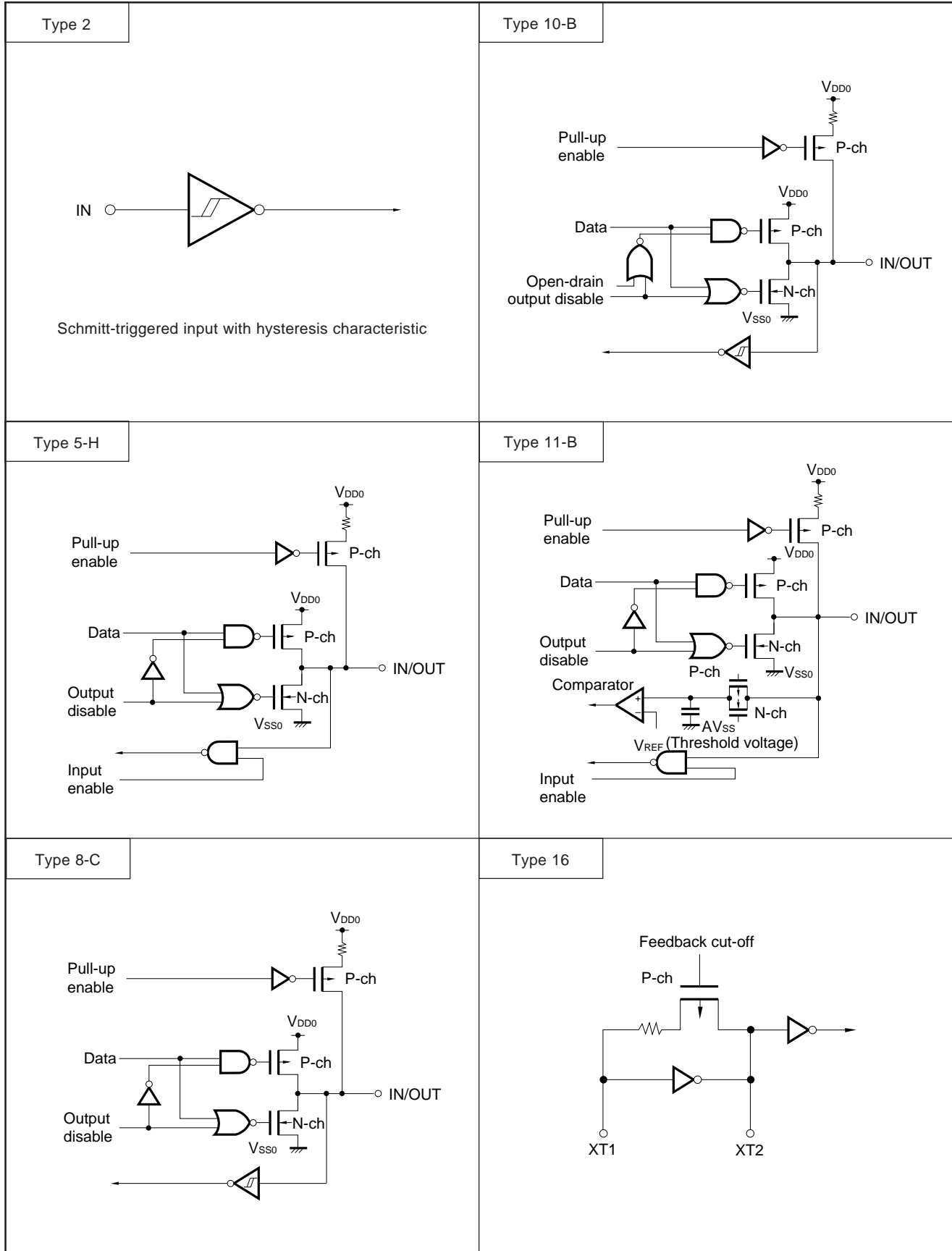
Table 3-1. Input/Output Circuit Type of Each Pin (1/2)

Pin Name	Input/output Circuit Type	I/O	Recommended Connection When Not Used
P00/INTP0/TI00	2	Input	Connect to V _{SS0} .
P01/INTP1/TI01	8-C	Input/output	Independently connect to V _{SS0} through resistor.
P02/INTP2			
P03/INTP3			
P04/INTP4			
P05/INTP5			
P07/XT1	16	Input	Connect to V _{DD0} .
P10/ANI0 to P17/ANI7	11-B	Input/output	Independently connect to V _{DD0} or V _{SS0} through resistor.
P25/SI0/SB0/SDA0	10-B		
P26/SO0/SB1/SDA1			
P27/SCK0/SCL			
P30/TO0	5-H		
P31/TO1			
P32/TO2			
P33/TI1	8-C		
P34/TI2			

Table 3-1. Input/Output Circuit Type of Each Pin (2/2)

Pin Name	Input/output Circuit Type	I/O	Recommended Connection When Not Used
P35/PCL	5-H	Input/output	Independently connect to V _{DD0} or V _{SS0} through resistor.
P36/BUZ			
P37			
P70/SI2/RxD	8-C		
P71/SO2/TxD	5-H		
P72/SCK2/ASCK	8-C		
P80/S39 to P87/S32	17-C		
P90/S31 to P97/S24			
P100 to P103	5-H		
P110/SI3	8-C		
P111/SO3			
P112/SCK3			
P113/TxD			
P114/RxD			
P115 to P117			
S0 to S23	17-B	Output	Leave unconnected.
COM0 to COM3	18-A		
V _{LC0} to V _{LC2}	—	—	—
BIAS	—	—	—
RESET	2	Input	—
XT2	16	—	Leave unconnected.
AV _{REF}	—		Connect to V _{SS0} .
AV _{SS}			Connect to V _{SS0} .
IC			Connect directly to V _{SS0} or V _{SS1} .

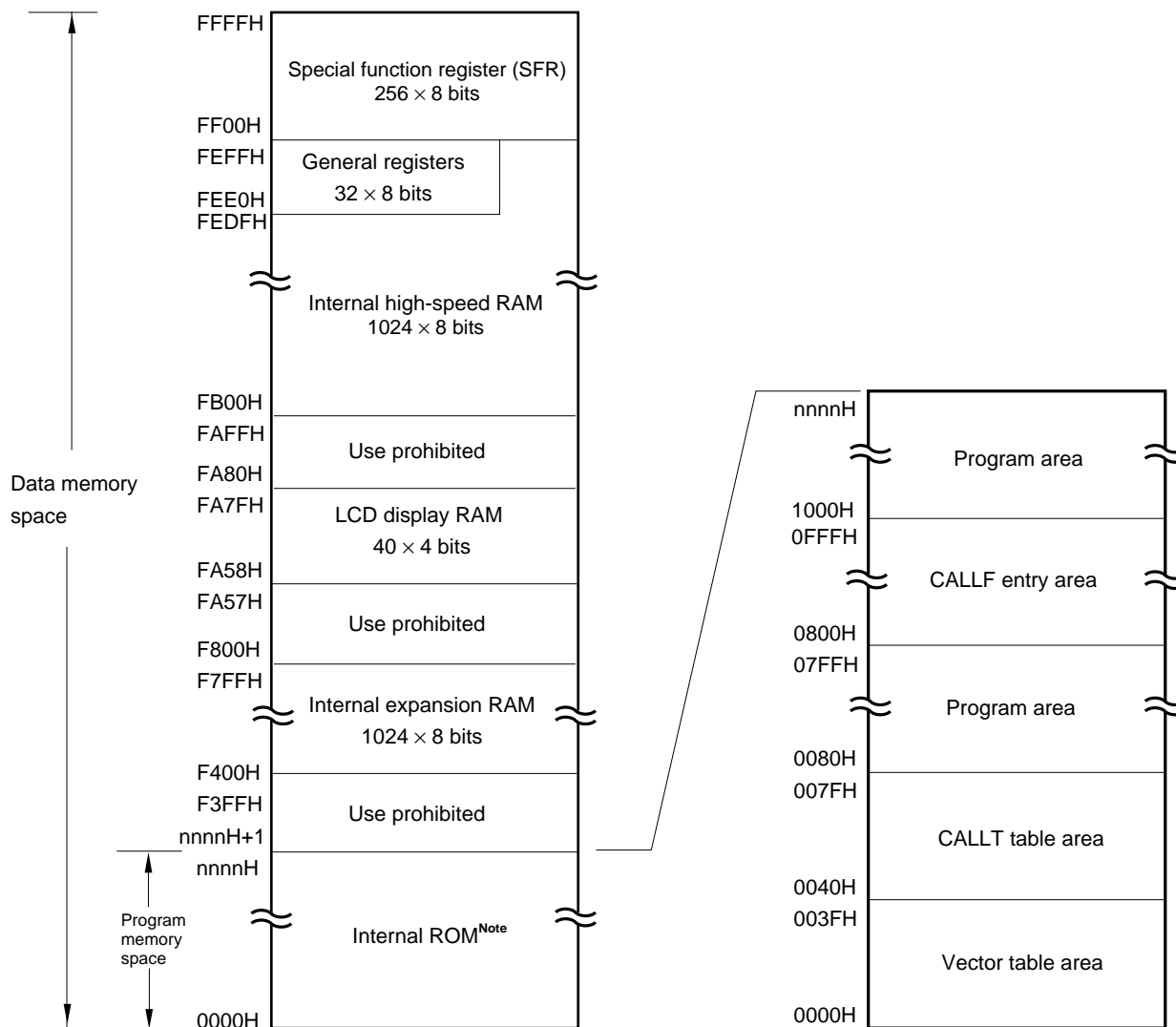
Figure 3-1. Pin Input/Output Circuits (1/2)



4. MEMORY SPACE

The memory map of μPD780306Y and 780308Y is shown in Figure 4-1.

Figure 4-1. Memory Map



Note The capacity of Internal ROM differs according to product. (refer to the following table.)

Product Name	Last Address of Internal ROM nnnnH
μPD780306Y	BFFFH
μPD780308Y	EFFFH

5. PERIPHERAL HARDWARE FUNCTION FEATURE

5.1 PORT

There are two kinds of I/O port.

• CMOS input (P00, P07)	: 2
• CMOS input/output (P01 to P05, Port 1 to 3, 7 to 11)	: 55
Total	: 57

Table 5-1. Functions of Ports

Name	Pin Name	Function
Port 0	P00, P07	Dedicated input port
	P01 to P05	Input/output port. Input/output specifiable bit-wise. When used as input port, on-chip pull-up resistor can be used by software.
Port 1	P10 to P17	Input/output port. Input/output specifiable bit-wise. When used as input port, on-chip pull-up resistor can be used by software.
Port 2	P25 to P27	Input/output port. Input/output specifiable bit-wise. When used as input port, on-chip pull-up resistor can be used by software.
Port 3	P30 to P37	Input/output port. Input/output specifiable bit-wise. When used as input port, on-chip pull-up resistor can be used by software.
Port 7	P70 to P72	Input/output port. Input/output specifiable bit-wise. When used as input port, on-chip pull-up resistor can be used by software.
Port 8	P80 to P87	Input/output port. Input/output specifiable bit-wise. When used as input port, on-chip pull-up resistor can be used by software. Input/output port/segment signal output function specifiable in 2-bit units by LCD display control register (LCDC).
Port 9	P90 to P97	Input/output port. Input/output specifiable bit-wise. When used as input port, on-chip pull-up resistor can be used by software. Input/output port/segment signal output function specifiable in 2-bit units by LCD display control register (LCDC).
Port 10	P100 to P103	Input/output port. Input/output specifiable bit-wise. When used as input port, on-chip pull-up resistor can be used by software. Direct LED drive capability.
Port 11	P110 to P117	Input/output port. Input/output specifiable bit-wise. When used as input port, on-chip pull-up resistor can be used by software. Test flag (KRIF) is set to 1 by falling edge detection.

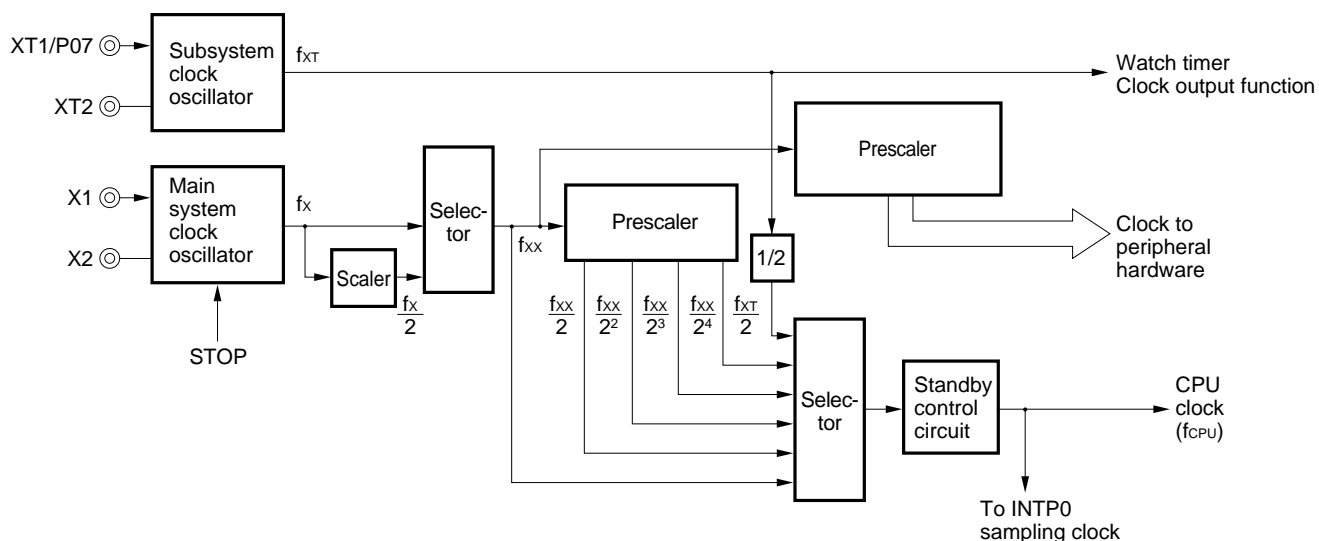
5.2 CLOCK GENERATOR

There are two kinds of clocks, main system clock and subsystem clock.

The minimum instruction execution time can also be changed.

- 0.4 μs/0.8 μs/1.6 μs/3.2 μs/6.4 μs/12.8 μs (main system clock: in 5.0 MHz operation)
- 122 μs (subsystem clock: in 32.768 kHz operation)

Figure 5-1. Clock Generator Block Diagram



5.3 TIMER/EVENT COUNTER

Five timer/event counter channels are incorporated.

- 16-bit timer/event counter : 1 channel
- 8-bit timer/event counter : 2 channels
- Watch timer : 1 channel
- Watchdog timer : 1 channel

Table 5-2. Timer/Event Counter Types and Functions

		16-bit Timer/Event Counter	8-bit Timer/Event Counter	Watch Timer	Watchdog Timer
Type	Interval timer	1 channel	2 channels	1 channel	1 channel
	External event counter	1 channel	2 channels	–	–
Function	Timer output	1 output	2 outputs	–	–
	PWM output	1 output	–	–	–
	Pulse width measurement	2 inputs	–	–	–
	Square wave output	1 output	2 outputs	–	–
	One-shot pulse output	1 output	–	–	–
	Interrupt request	2	2	1	1
	Test input	–	–	1 input	–

Figure 5-2. 16-Bit Timer/Event Counter Block Diagram

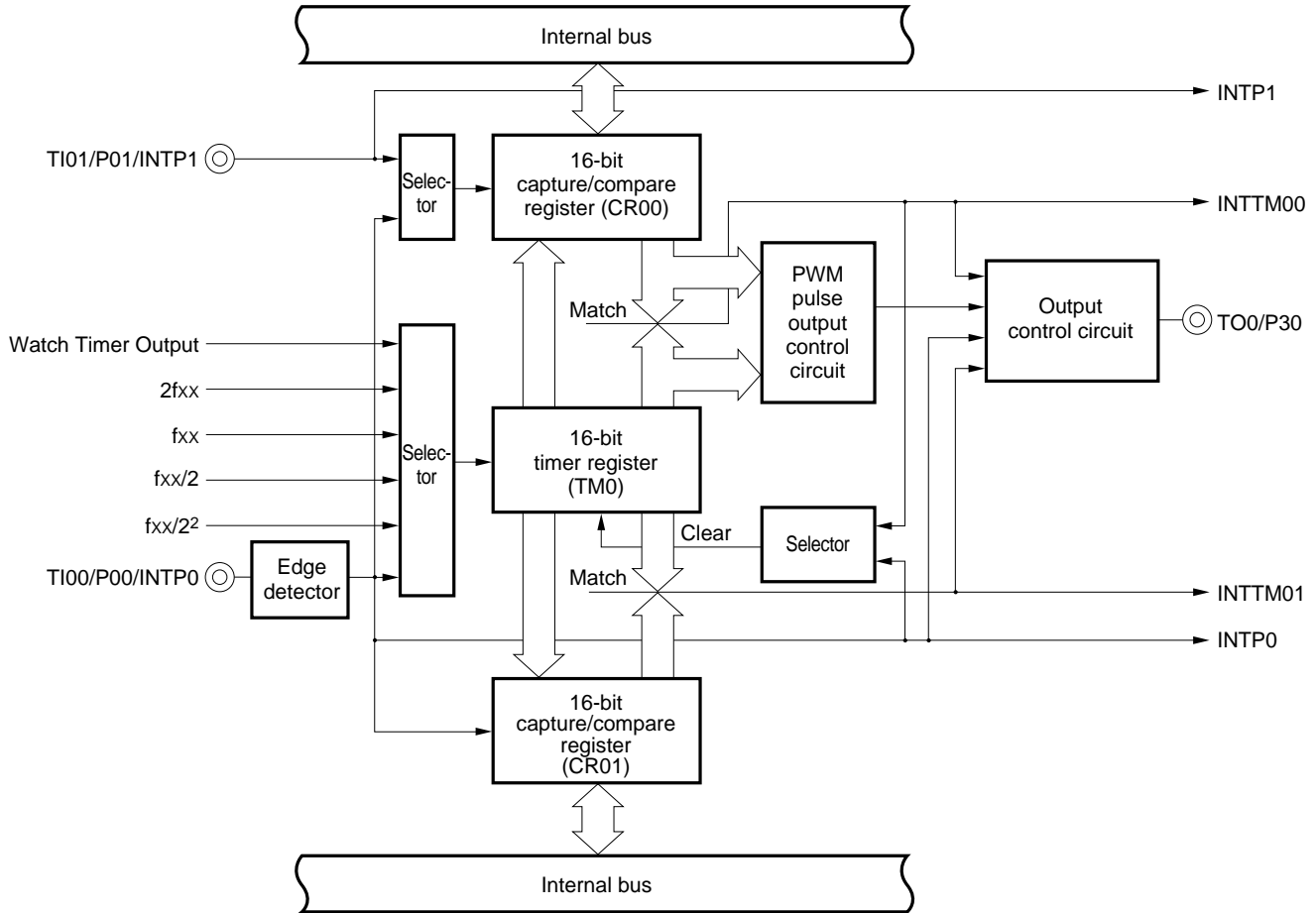


Figure 5-3. 8-Bit Timer/Event Counter Block Diagram

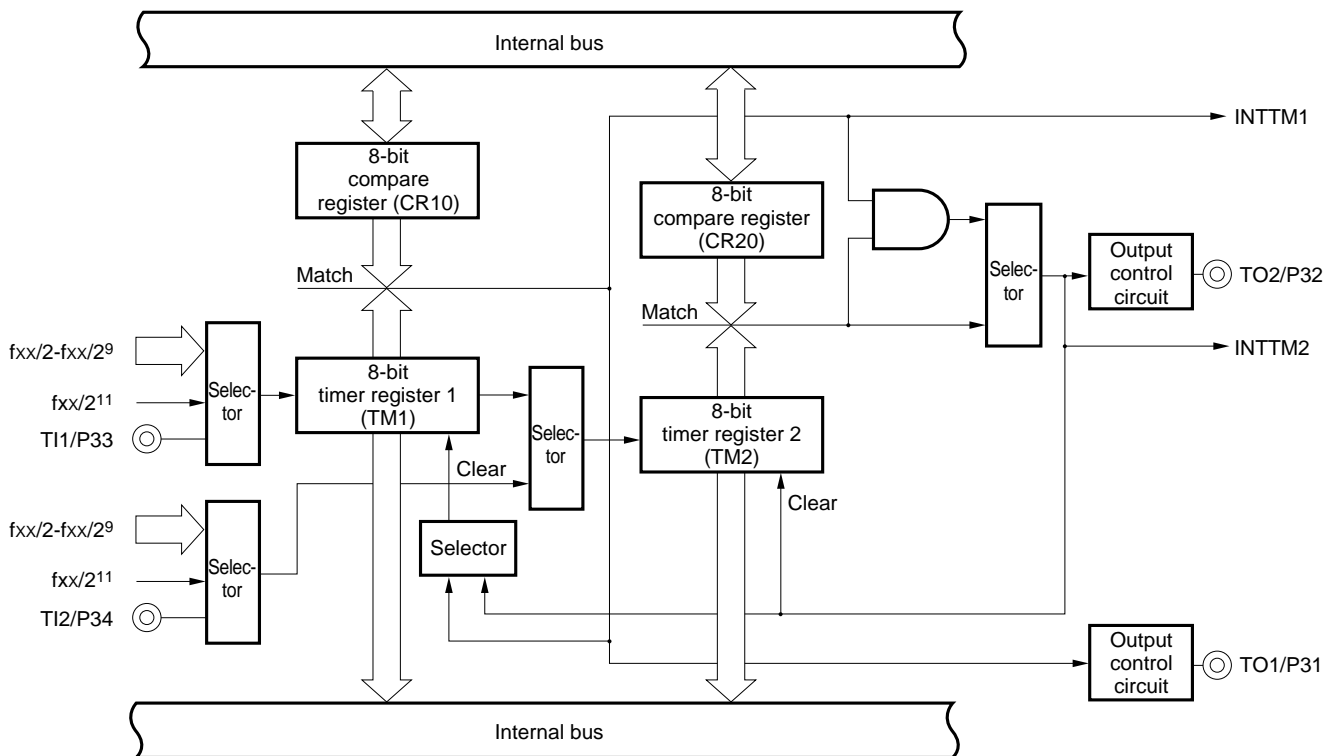


Figure 5-4. Watch Timer Block Diagram

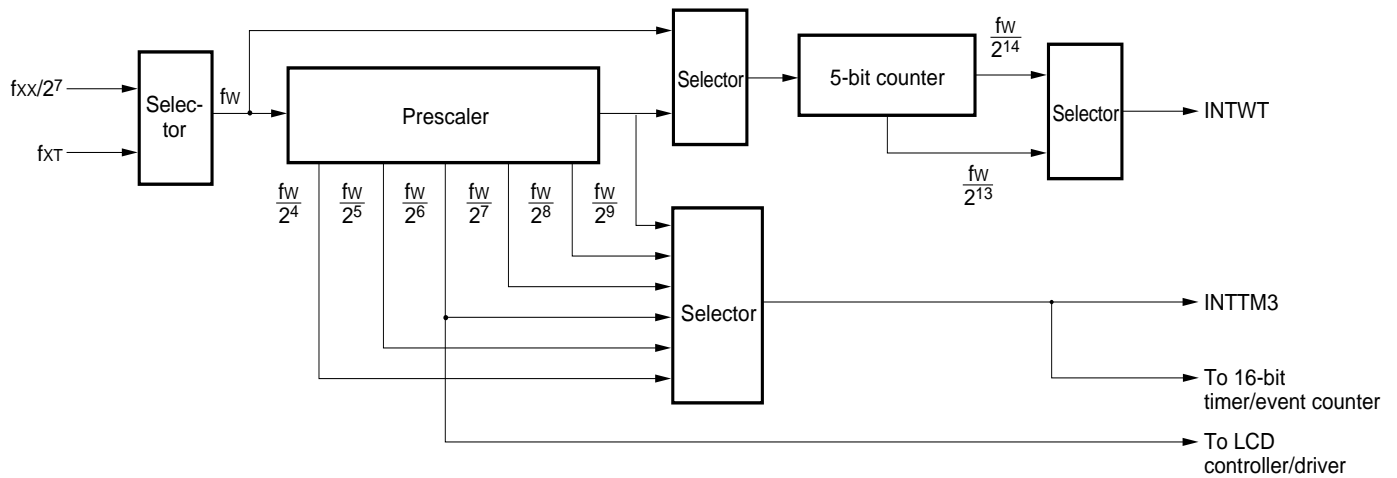
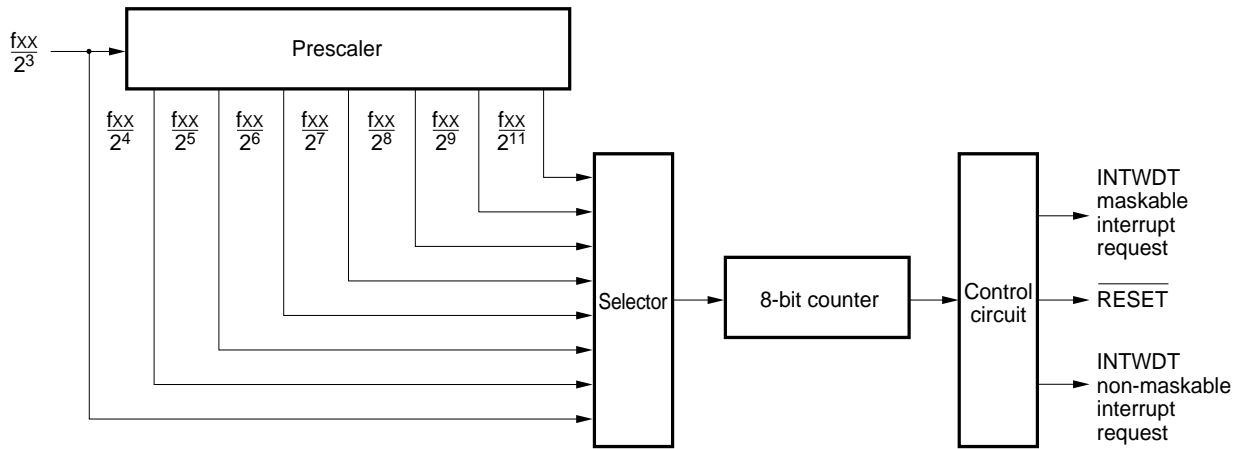


Figure 5-5. Watchdog Timer Block Diagram

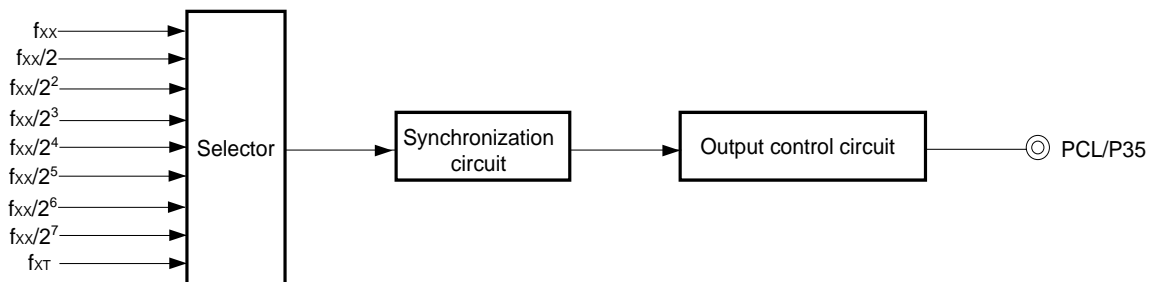


5.4 CLOCK OUTPUT CONTROL CIRCUIT

Clocks of the following frequency can be output as clock outputs.

- 19.5 kHz/39.1kHz/78.1 kHz/156 kHz/313 kHz/625 kHz/1.25 MHz/2.5 MHz/5.0 MHz (main system clock: in 5.0 MHz operation)
- 32.768 kHz (subsystem clock: in 32.768 kHz operation)

Figure 5-6. Clock Output Control Circuit Block Diagram

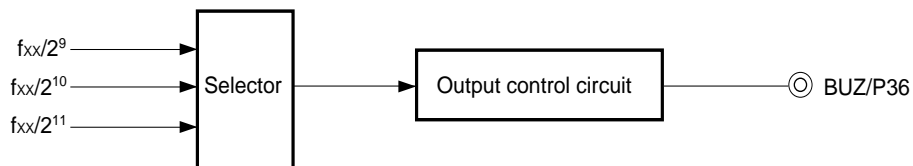


5.5 BUZZER OUTPUT CONTROL CIRCUIT

Clocks of the following frequency can be output as buzzer outputs.

- 1.2 kHz/2.4 kHz/4.9 kHz/9.8 kHz (main system clock : in 5.0 MHz operation)

Figure 5-7. Buzzer Output Control Circuit Block Diagram



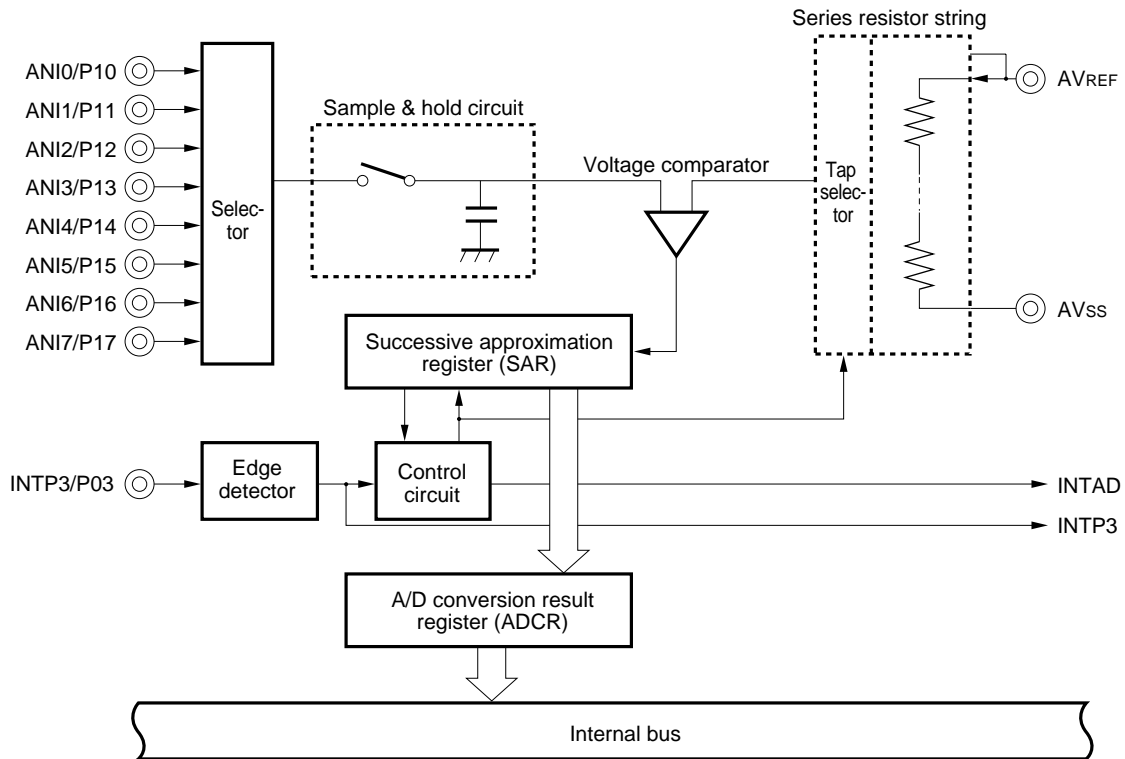
5.6 A/D CONVERTER

Eight 8-bit resolution A/D converter channels are incorporated.

The following two types of start-up method are available.

- Hardware start
- Software start

Figure 5-8. A/D Converter Block Diagram



5.7 SERIAL INTERFACE

Three clocked serial interface channels are incorporated.

- Serial interface channel 0
- Serial interface channel 2
- Serial interface channel 3

Table 5-3. Serial Interface Channel Block Diagram

Function	Serial Interface Channel 0	Serial Interface Channel 2	Serial Interface Channel 3
3-wire serial I/O mode	○ (MSB/LSB-first switchable)	○ (MSB/LSB-first switchable)	○ (MSB/LSB-first switchable)
I ² C (Inter IC) bus mode	○ (MSB-first)	—	—
2-wire serial I/O mode	○ (MSB-first)	—	—
Asynchronous serial interface (UART) mode	—	○ (With dedicated baud rate generator, data I/O pin switch function)	—

Figure 5-9. Serial Interface Channel 0 Block Diagram

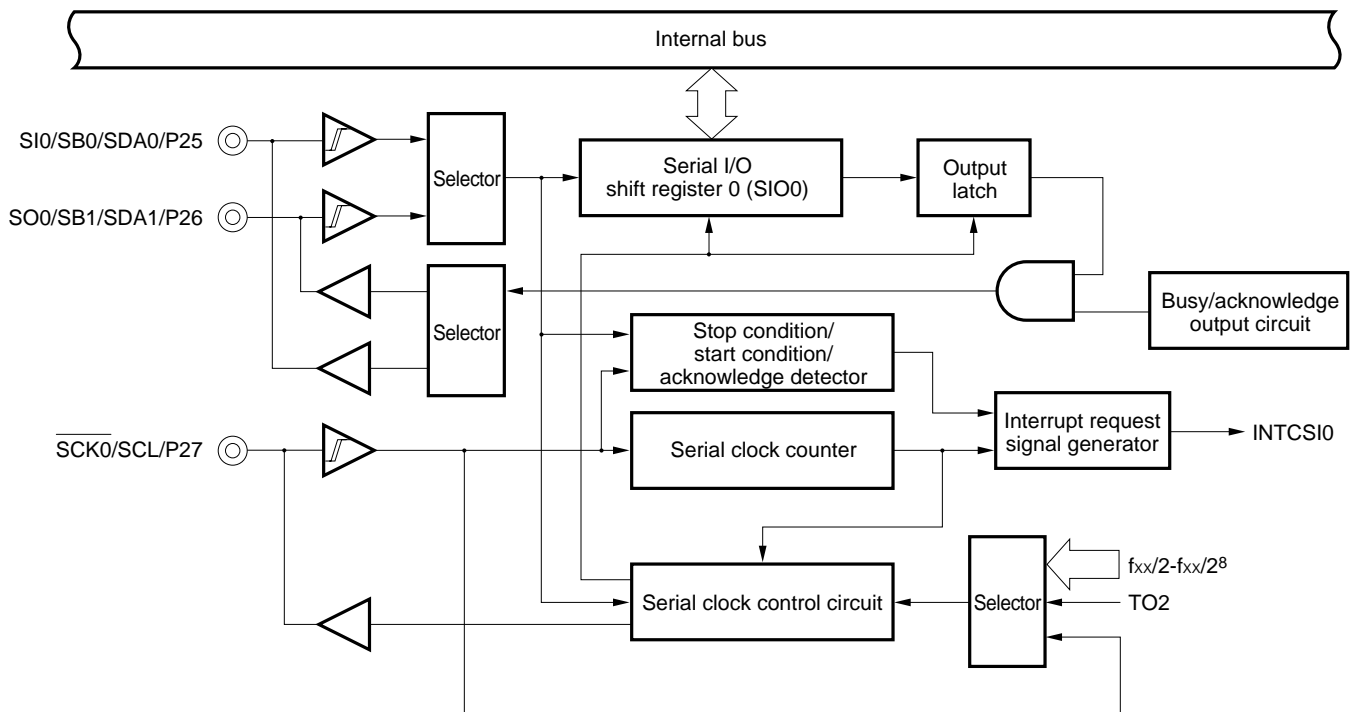


Figure 5-10. Serial Interface Channel 2 Block Diagram

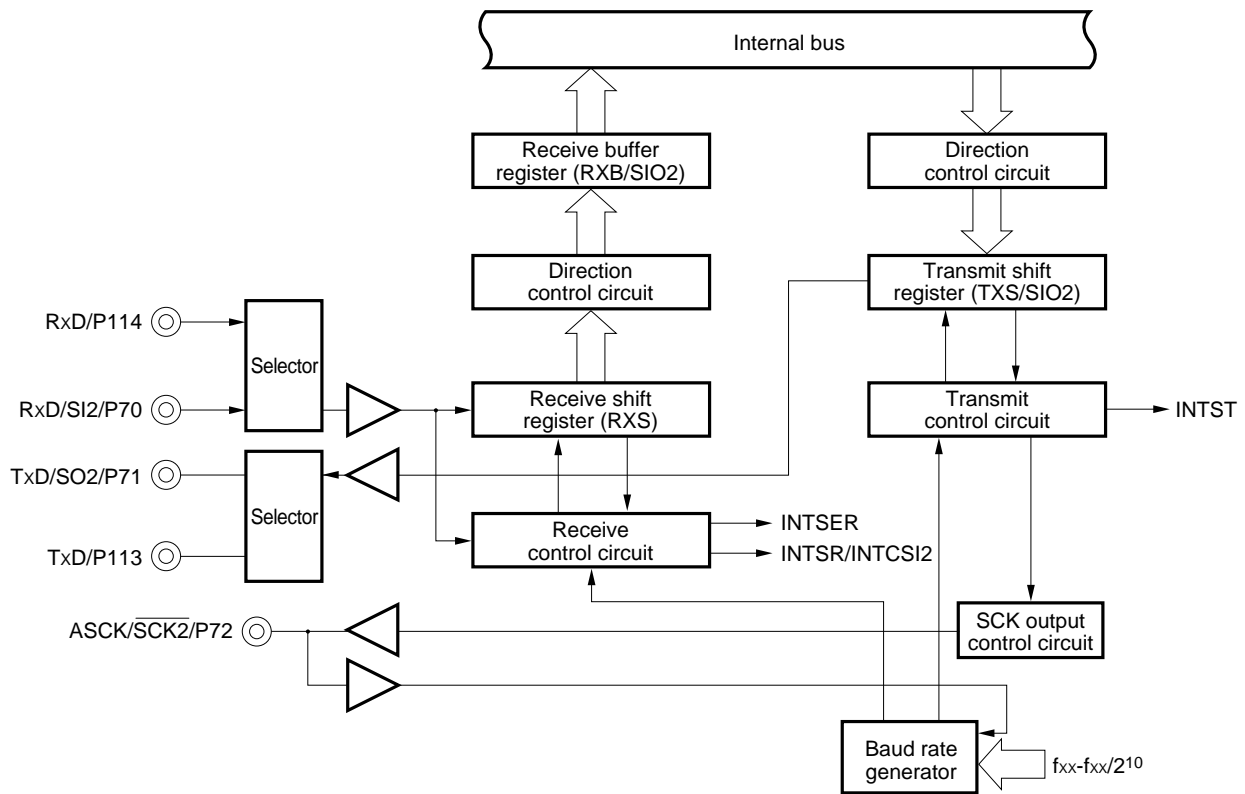
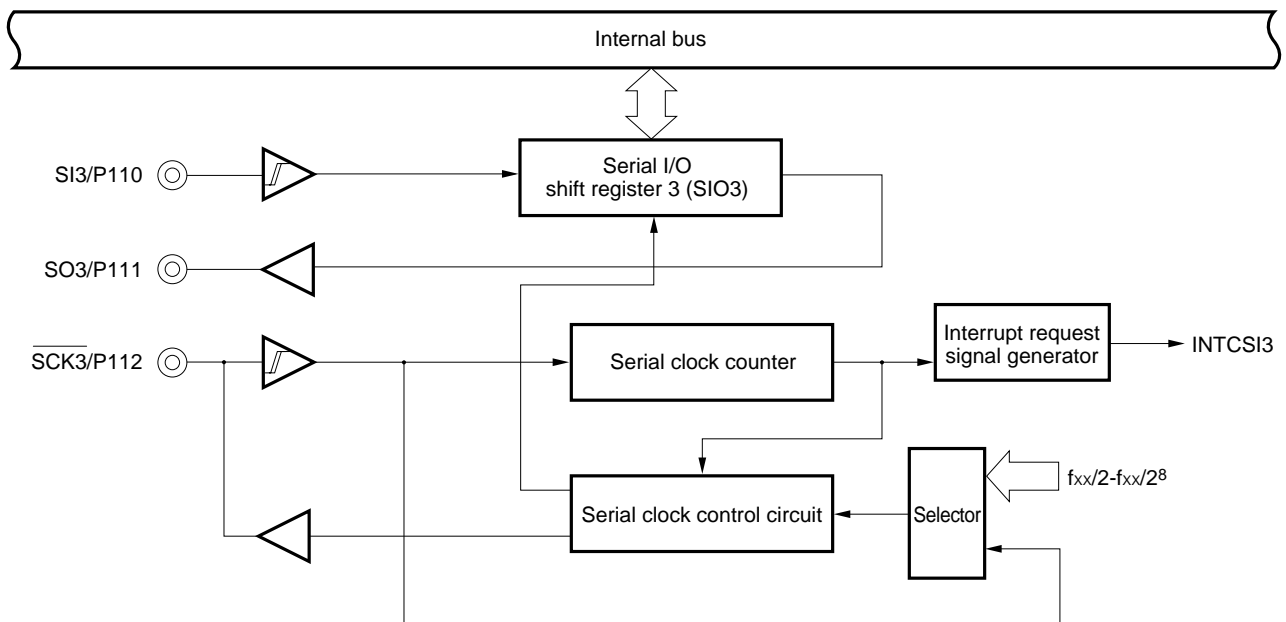


Figure 5-11. Serial Interface Channel 3 Block Diagram



5.8 LCD CONTROLLER/DRIVER

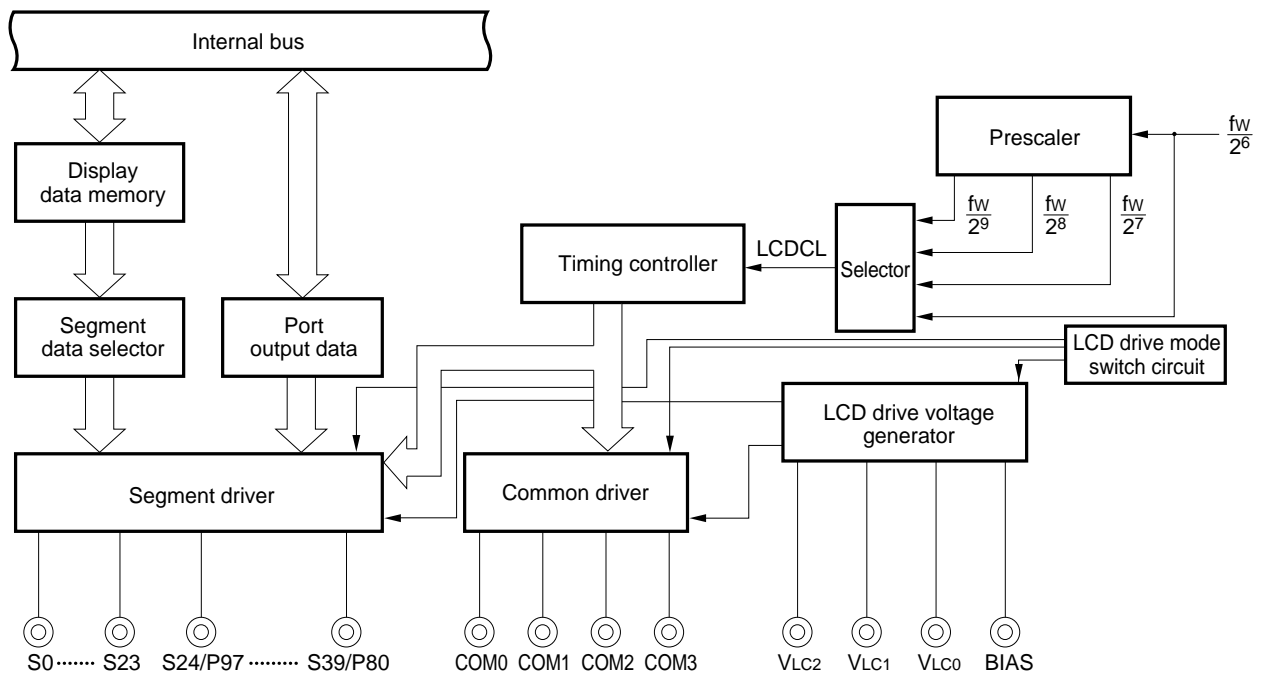
An LCD controller/driver with the following functions is incorporated.

- Selection of 5 types of display mode
- 16 of the segment signal of outputs can be switched to input/output ports in units of 2.
(P80/S39 to P87/S32, P90/S31 to P97/S24)

Table 5-4. Display Mode Types and Maximum Number of Display Pixels

Bias Method	Time Multiplexing	Common Signal Used	Maximum Number of Display Pixels
—	Static	COM0 (COM1 to COM3)	40 (40 segments × 1 common)
1/2	2	COM0, COM1	80 (40 segments × 2 commons)
	3	COM0 to COM2	
1/3	3	COM0 to COM2	120 (40 segments × 3 commons)
	4	COM0 to COM3	
			160 (40 segments × 4 commons)

Figure 5-12. LCD Controller/Driver Block Diagram



6. INTERRUPT FUNCTIONS AND TEST FUNCTIONS

6.1 INTERRUPT FUNCTIONS

There are twenty-one of interrupt sources of three different kinds, as shown below.

- Non-maskable : 1
- Maskable : 19
- Software : 1

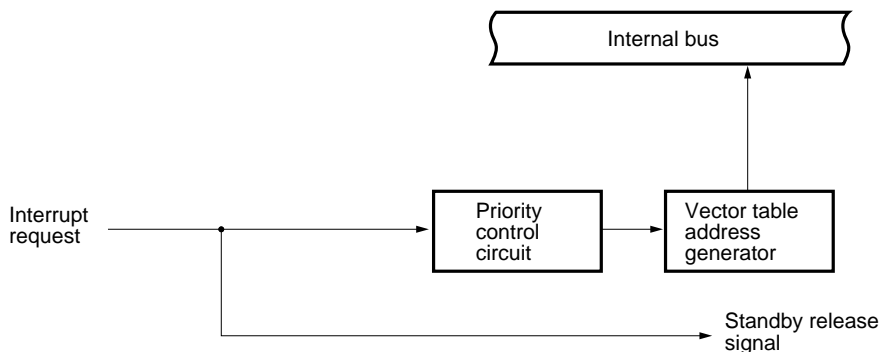
Table 6-1. Interrupt Source List

Interrupt Type	Default Priority ^{Note1}	Interrupt Source		Internal/External	Vector Table Address	Basic Configuration Type ^{Note2}
		Name	Trigger			
Non-maskable	—	INTWDT	Watchdog timer overflow (with watchdog timer mode 1 selected)	Internal	0004H	(A)
Maskable	0	INTWDT	Watchdog timer overflow (with interval timer mode selected)			External
	1	INTP0	Pin input edge detection	(D)		
	2	INTP1				
	3	INTP2				
	4	INTP3				
	5	INTP4				
	6	INTP5				
	7	INTCSI0	Serial interface channel 0 transfer termination		Internal	0014H
	8	INTSER	Serial interface channel 2 UART reception error generation	0018H		
	9	INTSR	Serial interface channel 2 UART reception termination	001AH		
		INTCSI2	Serial interface channel 2 3-wire transfer termination			
	10	INTST	Serial interface channel 2 UART transmission termination	001CH		
	11	INTTM3	Reference time interval signal from watch timer	001EH		
	12	INTTM00	16-bit timer register and capture/compare register (CR00) match signal generation	0020H		
	13	INTTM01	16-bit timer register and capture/compare register (CR01) match signal generation	0022H		
	14	INTTM1	8-bit timer/event counter 1 match signal generation	0024H		
	15	INTTM2	8-bit timer/event counter 2 match signal generation	0026H		
16	INTAD	A/D converter conversion termination	0028H			
17	INTCSI3	Serial interface channel 3 transfer termination	002AH			
Software	—	BRK	BRK instruction execution	—	003EH	(E)

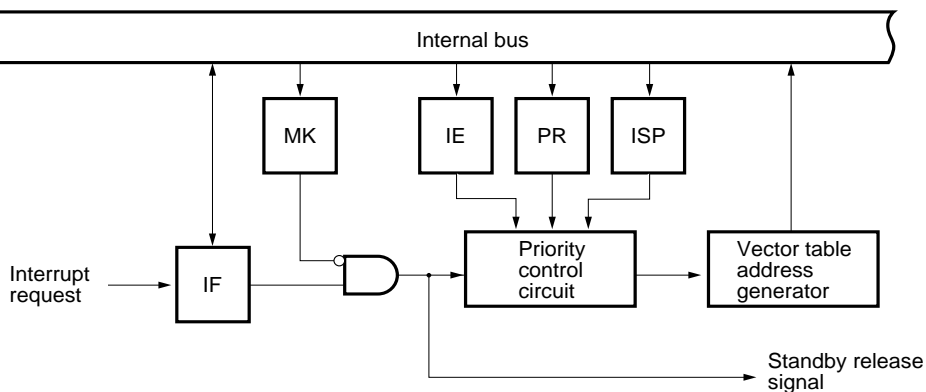
- Notes**
1. Default priority is a priority order when more than one maskable interrupt source is generated simultaneously. 0 is the highest and 17 the lowest.
 2. Basic configuration types (A) to (E) correspond to those shown on the next page.

Figure 6-1. Basic Configuration of Interrupt Functions (1/2)

(A) Internal non-maskable interrupt



(B) Internal maskable interrupt



(C) External maskable interrupt (INTP0)

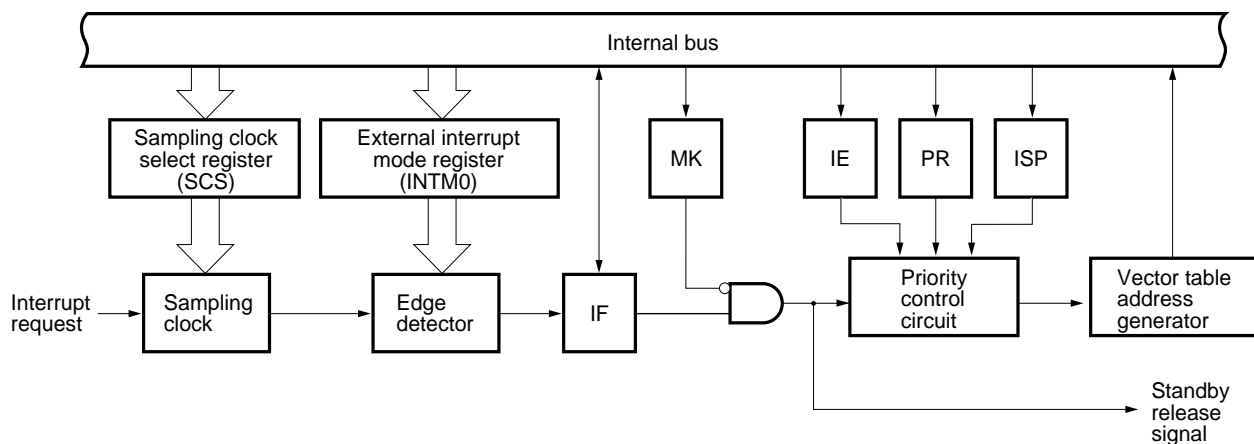
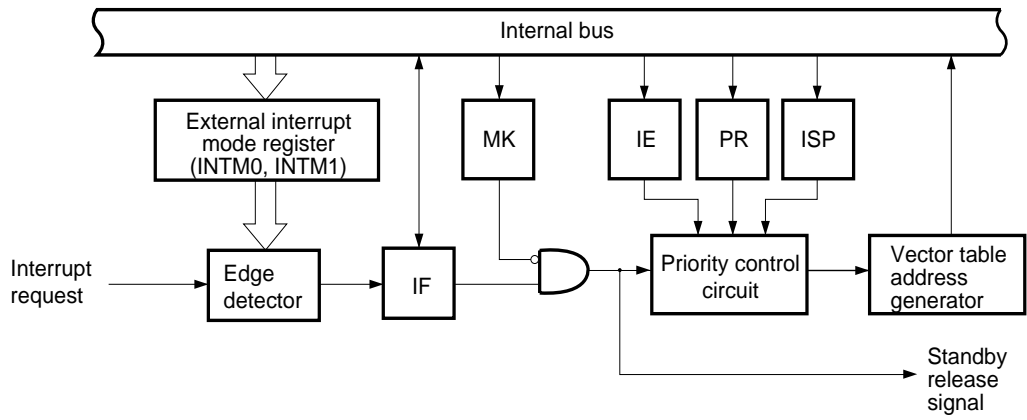
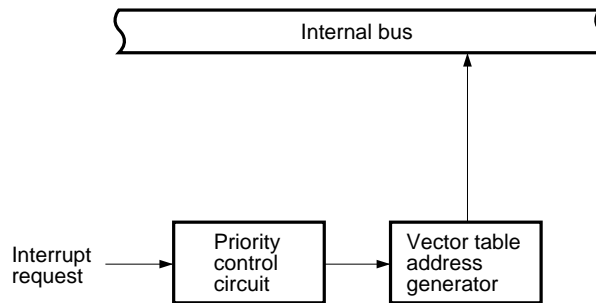


Figure 6-1. Basic Configuration of Interrupt Functions (2/2)

(D) External maskable interrupt (except INTP0)



(E) Software interrupt



- IF : Interrupt request flag
- IE : Interrupt enable flag
- ISP : In-service priority flag
- MK : Interrupt mask flag
- PR : Priority hung-up flag

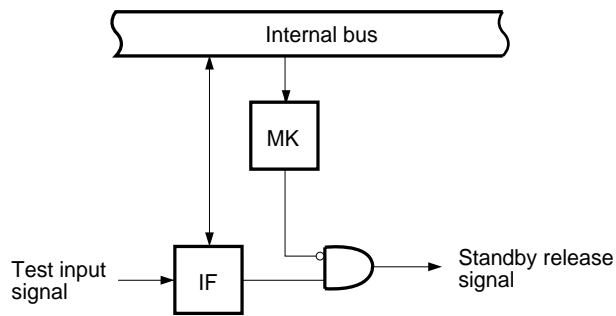
6.2 TEST FUNCTIONS

There are two test functions as shown in Table 6-2.

Table 6-2. Test Input Source List

Test Input Source		Internal/External
Name	Trigger	
INTWT	Watch timer overflow	Internal
INTPT11	Port 11 falling edge detection	External

Figure 6-2. Basic Configuration of Test Function



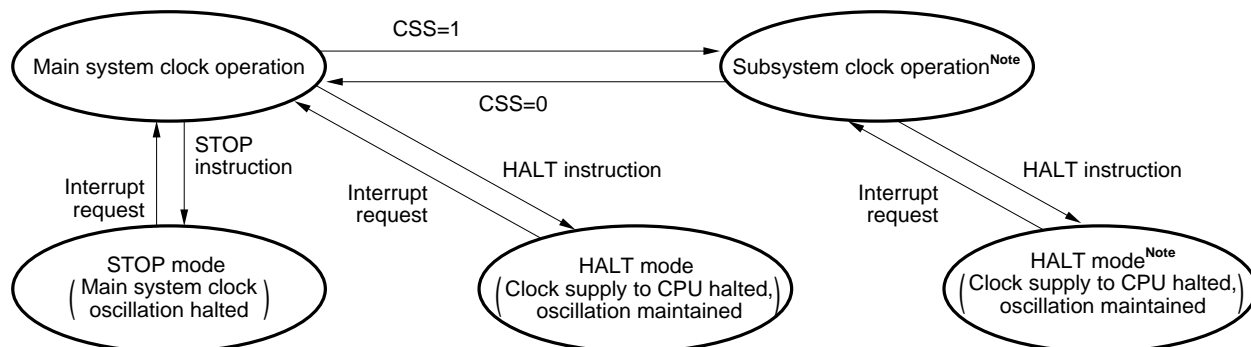
IF : Test input flag
 MK : Test mask flag

7. STANDBY FUNCTION

The standby function is a function to reduce the current consumption and there are the following two kinds of standby functions.

- HALT mode : Halts CPU operating clock and can reduce average current consumption by the intermittent operation along with the normal operation.
- STOP mode : Halts main system clock oscillation. Halts all operations with the main system clock and sets ultra-low current consumption state with subsystem clock only.

Figure 7-1. Standby Function



Note Halting the main system clock enables the current consumption to be reduced.

When the CPU is operated by the subsystem clock, the main system clock should be halted by setting the bit 7 (MCC) of the processor clock control register (PCC). The STOP instruction is not available.

Caution When the main system clock is stopped and the system is operated by the subsystem clock, the main system clock should be returned to after securing the oscillation stabilization time by a program.

8. RESET FUNCTION

There are the following two kinds of resetting methods.

- External reset by $\overline{\text{RESET}}$ pin.
- Internal reset by watchdog timer hung-up time detection.

9. INSTRUCTION SET

(1) 8-bit instruction

MOV, XCH, ADD, ADDC, SUB, SUBS, AND, OR, XOR, CMP, MULU, DIVUW, INC, DEC, ROR, ROL, RORC, ROLC, ROR4, ROL4, PUSH, POP, DBNZ

2nd Operand 1st Operand	#byte	A	r ^{Note}	sfr	saddr	!addr16	PSW	[DE]	[HL]	[HL+byte] [HL+B] [HL+C]	\$addr16	1	None
A	ADD ADDC SUB SUBC AND OR XOR CMP		MOV XCH ADD ADDC SUB SUBC AND OR XOR CMP	MOV XCH	MOV XCH ADD ADDC SUB SUBC AND OR XOR CMP	MOV XCH ADD ADDC SUB SUBC AND OR XOR CMP	MOV	MOV XCH	MOV XCH ADD ADDC SUB SUBC AND OR XOR CMP	MOV XCH ADD ADDC SUB SUBC AND OR XOR CMP		ROR ROL RORC ROLC	
r	MOV	MOV ADD ADDC SUB SUBC AND OR XOR CMP											INC DEC
B, C											DBNZ		
sfr	MOV	MOV											
saddr	MOV ADD ADDC SUB SUBC AND OR XOR CMP	MOV									DBNZ		INC DEC
!addr16		MOV											
PSW	MOV	MOV											PUSH POP
[DE]		MOV											
[HL]		MOV											ROR4 ROL4
[HL+byte] [HL+B] [HL+C]		MOV											
X													MULU
C													DIVUW

Note Except r = A

(2) 16-bit instruction

MOVW, XCHW, ADDW, SUBW, CMPW, PUSH, POP, INCW, DECW

2nd Operand 1st Operand	#word	AX	rp ^{Note}	sfrp	saddrp	!addr16	SP	None
AX	ADDW SUBW CMPW		MOVW XCHW	MOVW	MOVW	MOVW	MOVW	
rp	MOVW	MOVW ^{Note}						INCW, DECW PUSH, POP
sfrp	MOVW	MOVW						
saddrp	MOVW	MOVW						
!addr16		MOVW						
SP	MOVW	MOVW						

Note Only when rp = BC, DE, HL

(3) Bit manipulation instruction

MOV1, AND1, OR1, XOR1, SET1, CLR1, NOT1, BT, BF, BTCLR

2nd Operand 1st Operand	A.bit	sfr.bit	saddr.bit	PSW.bits	[HL].bit	CY	\$addr16	None
A.bit						MOV1	BT BF BTCLR	SET1 CLR1
sfr.bit						MOV1	BT BF BTCLR	SET1 CLR1
saddr.bit						MOV1	BT BF BTCLR	SET1 CLR1
PSW.bit						MOV1	BT BF BTCLR	SET1 CLR1
[HL].bit						MOV1	BT BF BTCLR	SET1 CLR1
CY	MOV1 AND1 OR1 XOR1	MOV1 AND1 OR1 XOR1	MOV1 AND1 OR1 XOR1	MOV1 AND1 OR1 XOR1	MOV1 AND1 OR1 XOR1			SET1 CLR1 NOT1

(4) Call instruction/branch instruction

CALL, CALLF, CALLT, BR, BC, BNC, BZ, BNZ, BT, BF, BTCLR, DNZB

2nd Operand 1st Operand	AX	!addr16	!addr11	[addr5]	\$addr16
Basic instruction	BR	CALL BR	CALLF	CALLT	BR, BC, BNC, BZ, BNZ
Compound Instruction					BT, BF, BTCLR DBNZ

(5) Other instructions

ADJBA, ADJBS, BRK, RET, RETI, RETB, SEL, NOP, EI, DI, HALT, STOP

10. ELECTRICAL SPECIFICATIONS

ABSOLUTE MAXIMUM RATINGS (T_A = 25°C)

Parameter	Symbol	Test Conditions		Rating	Unit
Supply voltage	V _{DD}			-0.3 to +7.0	V
	AV _{REF}			-0.3 to V _{DD} + 0.3	V
	AV _{SS}			-0.3 to +0.3	V
Input voltage	V _I			-0.3 to V _{DD} + 0.3	V
Output voltage	V _O			-0.3 to V _{DD} + 0.3	V
Analog input voltage	V _{AN}	P10-P17	Analog input pin	AV _{SS} - 0.3 to AV _{REF} + 0.3	V
Output current, high	I _{OH}	1 pin		-10	V
		Total for P01-P05, P10-P17, P25-P27, P70-P72, P110-P117		-15	mA
		Total for P30-P37, P80-P87, P90-P97, P100-P117		-15	mA
Output current, low	I _{OL}	1 pin	Peak value	30	mA
			r.m.s. value	15 ^{Note}	mA
		Total for P01-P05, P10-P17, P110-P117	Peak value	60	mA
			r.m.s. value	40 ^{Note}	mA
		Total for P30-P37, P100-P103	Peak value	140	mA
			r.m.s. value	100 ^{Note}	mA
		Total for P25-P27, P70-P72, P80-P87, P90-P97	Peak value	50	mA
			r.m.s. value	20 ^{Note}	mA
Operating ambient temperature	T _A			-40 to +85	°C
Storage temperature	T _{stg}			-65 to +150	°C

Note The r.m.s. value should be calculated as follows: [r.m.s. value] = [Peak value] × √Duty

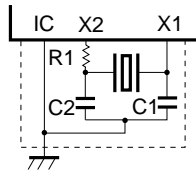
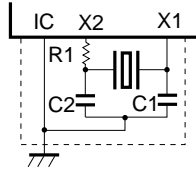
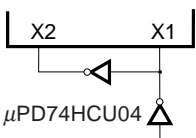
Caution The product quality may be damaged even if a value of only one of the above parameters exceeds the absolute maximum rating or any value exceeds the absolute maximum rating for an instant. That is, the absolute maximum rating is a rating value which may cause a product to be damaged physically. The absolute maximum rating values must therefore be observed in using the product.

Remark Unless specified otherwise, the characteristics of dual-function pins are the same as the those of port pins.

CAPACITANCE (T_A = 25 °C, V_{DD} = V_{SS} = 0 V)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
Input capacitance	C _{IN}	f = 1 MHz unmeasured pins returned to 0 V.			15	pF
Output capacitance	C _{OUT}				15	pF
I/O capacitance	C _{IO}				15	pF

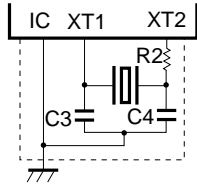
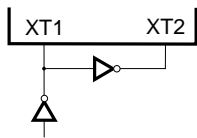
MAIN SYSTEM CLOCK OSCILLATION CIRCUIT CHARACTERISTICS (T_A = -40 to +85 °C, V_{DD} = 2.0^{Note 4} to 5.5 V)

Resonator	Recommended circuit	Parameter	Test conditions	MIN.	TYP.	MAX.	Unit
Ceramic resonator		Oscillator frequency (f _x) ^{Note 1}	V _{DD} = Oscillator voltage range	1		5	MHz
		Oscillation stabilization time ^{Note 2}	After V _{DD} reaches oscillator voltage range MIN.			4	ms
Crystal resonator		Oscillator frequency (f _x) ^{Note 1}	V _{DD} = Oscillator voltage range	1		5	MHz
		Oscillation stabilization time ^{Note 2}	V _{DD} = 4.5 to 5.5 V ^{Note 3} Note 3			10 30	ms
External clock		X1 input frequency (f _x) ^{Note 1}		1.0		5.0	MHz
		X1 input high/low level width (t _{xH} , t _{xL})			85		500

- Notes**
1. Indicates only oscillation circuit characteristics. Refer to **AC Characteristics** for instruction execution time.
 2. Time required to stabilize oscillation after reset or STOP mode release.
 3. After V_{DD} reaches the minimum oscillator voltage range.
 4. Actually, oscillation start voltage or over, and V_{DD} = 2.0 or over (For an external clock, V_{DD} = 2.0 or over is OK).

- Cautions**
1. When using the main system clock oscillator, wiring in the area enclosed with the broken line should be carried out as follows to avoid an adverse effect from wiring capacitance.
 - Wiring should be as short as possible.
 - Wiring should not cross other signal lines.
 - Wiring should not be placed close to a varying high current.
 - The potential of the oscillator capacitor ground should be the same as V_{SS}.
 - Do not ground it to the ground pattern in which a high current flows.
 - Do not fetch a signal from the oscillator.
 2. If the main system clock oscillation circuit is operated by the subsystem clock when the main system clock is stopped, reswitching to the main system clock should be performed after the stable oscillation time has been obtained by the program.

SUBSYSTEM CLOCK OSCILLATOR CHARACTERISTICS (T_A = -40 to +85°C, V_{DD} = 2.0^{Note 4} to 5.5 V)

Resonator	Recommended Circuit	Parameter	Test Conditions	MIN.	TYP.	MAX.	Unit
Crystal resonator		Oscillator frequency (f _{XT}) ^{Note 1}	V _{DD} = Oscillator voltage range	32	32.768	35	kHz
		Oscillation stabilization time ^{Note 2}	V _{DD} = 4.5 to 5.5 V ^{Note 3} Note 3		1.2	2	10
External clock		XT1 input frequency (f _{XT}) ^{Note 1}		32		100	kHz
		XT1 input high-/low-level width (t _{bXTH} /t _{bXTL})		5		15	μs

- Notes**
1. Indicates only oscillation circuit characteristics. Refer to **AC Characteristics** for instruction execution time.
 2. Time required to stabilize oscillation after V_{DD} has reached the minimum oscillation voltage range.
 3. After V_{DD} reaches the minimum oscillator voltage range.
 4. Actually, oscillation start voltage or over, and V_{DD} = 2.0 or over (For an external clock, V_{DD} = 2.0 or over is OK).

- Cautions**
1. When using the subsystem clock oscillator, wiring in the area enclosed with the broken line should be carried out as follows to avoid an adverse effect from wiring capacitance.
 - Wiring should be as short as possible.
 - Wiring should not cross other signal lines.
 - Wiring should not be placed close to a varying high current.
 - The potential of the oscillator capacitor ground should be the same as V_{SS}.
 - Do not ground it to the ground pattern in which a high current flows.
 - Do not fetch a signal from the oscillator.
 2. The subsystem clock oscillation circuit is designed as a low amplification circuit to provide low consumption current, causing misoperation to noise more frequently than the main system clock oscillation circuit. Special care should therefore be taken to wiring method when the subsystem clock is used.

RECOMMENDED OSCILLATION CIRCUIT CONSTANT

MAIN SYSTEM CLOCK: CERAMIC RESONATOR ($T_A = -40$ to $+85$ °C)

Manufacturer	Product Name	Frequency (MHz)	Recommended Circuit Constant			Oscillator Voltage Range	
			C1 (pF)	C2 (pF)	R1 (k Ω)	MIN. (V)	MAX. (V)
Matsushita Electronics Components Co., Ltd.	EFOEC2004A5	2.00	Built-in	Built-in	4.7	2.0	5.5
	EFOEC3584A4	3.58	Built-in	Built-in	0	2.0	5.5
	EFOEC419A4	4.19	Built-in	Built-in	0	2.0	5.5
	EFOEC4914A4	4.91	Built-in	Built-in	0	2.0	5.5
	EFOEC5004A4	5.00	Built-in	Built-in	0	2.0	5.5
TDK Corp.	CCR1000K2	1.00	150	150	0	2.0	5.5
	CCR3.58MC3	3.58	Built-in	Built-in	0	2.0	5.5
	CCR4.19MC3	4.19	Built-in	Built-in	0	2.0	5.5
	CCR4.91MC3	4.91	Built-in	Built-in	0	2.0	5.5
	CCR5.0MC3	5.00	Built-in	Built-in	0	2.0	5.5
Murata Mfg. Co., Ltd.	CSB1000J	1.00	100	100	2.2	2.0	5.5
	CSA2.00MG040	2.00	100	100	0	2.0	5.5
	CST2.00MG040	2.00	Built-in	Built-in	0	2.0	5.5
	CSA3.58MG	3.58	30	30	0	2.0	5.5
	CST3.58MGW	3.58	Built-in	Built-in	0	2.0	5.5
	CSA4.19MG	4.19	30	30	0	2.0	5.5
	CST4.19MGW	4.19	Built-in	Built-in	0	2.0	5.5
	CSA4.91MG	4.91	30	30	0	2.0	5.5
	CST4.91MGW	4.91	Built-in	Built-in	0	2.0	5.5
	CSA5.00MG	5.00	30	30	0	2.0	5.5
	CST5.00MGW	5.00	Built-in	Built-in	0	2.0	5.5

Caution The oscillation circuit constants and oscillation voltage range indicate conditions for stable oscillation but do not guarantee accuracy of the oscillation frequency. If the application circuit requires accuracy of the oscillation frequency, it is necessary to set the oscillation frequency in the application circuit. For this, it is necessary to directly contact the manufacturer of the resonator being used.

DC CHARACTERISTICS (T_A = -40 to +85°C, V_{DD} = 2.0 to 5.5 V)

Parameter	Symbol	Test Conditions		MIN.	TYP.	MAX.	Unit
Input voltage, high	V _{IH1}	P10-P17, P30-P32, P35-P37, P80-P87, P90-P97, P100-P103	V _{DD} = 2.7 to 5.5 V	0.7 V _{DD}		V _{DD}	V
				0.8 V _{DD}		V _{DD}	V
	V _{IH2}	P00-P05, P25-P27, P33, P34, P70-P72, P110-P117, RESET	V _{DD} = 2.7 to 5.5 V	0.8 V _{DD}		V _{DD}	V
				0.85 V _{DD}		V _{DD}	V
	V _{IH3}	X1, X2	V _{DD} = 2.7 to 5.5 V	V _{DD} -0.5		V _{DD}	V
				V _{DD} -0.2		V _{DD}	V
	V _{IH4}	XT1/P07, XT2	4.5 ≤ V _{DD} ≤ 5.5 V	0.8 V _{DD}		V _{DD}	V
			2.7 ≤ V _{DD} < 4.5 V	0.9 V _{DD}		V _{DD}	V
			2.0 ≤ V _{DD} < 2.7 V ^{Note}	0.9 V _{DD}		V _{DD}	V
	Input voltage, low	V _{IL1}	P10-P17, P30-P32, P35-P37, P80-P87, P90-P97, P100-P103	V _{DD} = 2.7 to 5.5 V	0		0.3 V _{DD}
				0		0.2 V _{DD}	V
V _{IL2}		P00-P05, P25-P27, P33, P34, P70-P72, P110-P117, RESET	V _{DD} = 2.7 to 5.5 V	0		0.2 V _{DD}	V
				0		0.15 V _{DD}	V
V _{IL3}		X1, X2	V _{DD} = 2.7 to 5.5 V	0		0.4	V
				0		0.2	V
V _{IL4}		XT1/P07, XT2	4.5 ≤ V _{DD} ≤ 5.5 V	0		0.2 V _{DD}	V
			2.7 ≤ V _{DD} < 4.5 V	0		0.1 V _{DD}	V
			2.0 ≤ V _{DD} < 2.7 V ^{Note}	0		0.1 V _{DD}	V
Output voltage, high		V _{OH}	V _{DD} = 4.5 to 5.5 V I _{OH} = -1 mA		V _{DD} -1.0		V _{DD}
	I _{OH} = -100 μA		V _{DD} -0.5		V _{DD}	V	
Output voltage, low	V _{OL1}	P100-P103	V _{DD} = 4.5 to 5.5 V, I _{OL} = 15 mA		0.6	2.0	V
		P01-P05, P10-P17, P25-P27, P30-P37, P70-P72, P80-P87, P90-P97, P110-P117	V _{DD} = 4.5 to 5.5 V, I _{OL} = 1.6 mA			0.4	V
	V _{OL2}	SB0, SB1, SCK0	V _{DD} = 4.5 to 5.5 V, open-drain, pulled up (R = 1 kΩ)			0.2 V _{DD}	V
	V _{OL3}	I _{OL} = 400 μA				0.5	V

Note When used as P07, the inverse phase of P07 should be input to XT2 using an inverter.

Remark Unless specified otherwise, the characteristics of dual-function pins are the same as the those of port pins.

DC CHARACTERISTICS (T_A = -40 to +85 °C, V_{DD} = 2.0 to 5.5 V)

Parameter	Symbol	Test Conditions		MIN.	TYP.	MAX.	Unit
Input leakage current, high	I _{LIH1}	V _{IN} = V _{DD}	P00-P05, P10-P17, P25-P27, P30-P37, P70-P72, P80-P87, P90-P97, P100-P103, P110-P117			3	μA
	I _{LIH2}		X1, X2, XT1/P07, XT2			20	μA
Input leakage current, low	I _{LIL1}	V _{IN} = 0 V	P00-P05, P10-P17, P25-P27, P30-P37, P70-P72, P80-P87, P90-P97, P100-P103, P110-P117			-3	μA
	I _{LIL2}		X1, X2, XT1/P07, XT2			-20	μA
Output leakage current, high	I _{LOH}	V _{OUT} = V _{DD}				3	μA
Output leakage current, low	I _{LOL}	V _{OUT} = 0 V				-3	μA
Software pull-up resistor	R	V _{IN} = 0 V	P01-P05, P10-P17, P25-P27, P30-P37, P70-P72, P80-P87, P90-P97, P100-P103, P110-P117	15	45	90	kΩ
Supply current ^{Note 1}	I _{DD1}	5.00 MHz, Crystal oscillation (f _{xx} = 2.5 MHz) ^{Note 2} operating mode	V _{DD} = 5.0 V ± 10 % ^{Note 5}		4	12	mA
			V _{DD} = 3.0 V ± 10 % ^{Note 6}		0.6	1.8	mA
			V _{DD} = 2.2 V ± 10 % ^{Note 6}		0.35	1.05	mA
			V _{DD} = 5.0 V ± 10 % ^{Note 5}		6.5	19.5	mA
			V _{DD} = 3.0 V ± 10 % ^{Note 6}		0.8	2.4	mA
			V _{DD} = 2.2 V ± 10 %				
	I _{DD2}	5.00 MHz, Crystal oscillation (f _{xx} = 2.5 MHz) ^{Note 2} HALT mode	V _{DD} = 5.0 V ± 10 %		1.4	4.2	mA
			V _{DD} = 3.0 V ± 10 %		500	1500	μA
			V _{DD} = 2.2 V ± 10 %		280	840	μA
			V _{DD} = 5.0 V ± 10 %		1.6	4.8	mA
	I _{DD3}	32.768 kHz, Crystal oscillation operating mode ^{Note 4}	V _{DD} = 3.0 V ± 10 %		650	1950	μA
			V _{DD} = 2.2 V ± 10 %		60	120	μA
	I _{DD4}	32.768 kHz, Crystal oscillation HALT mode ^{Note 4}	V _{DD} = 5.0 V ± 10 %		32	64	μA
			V _{DD} = 3.0 V ± 10 %		24	48	μA
			V _{DD} = 2.2 V ± 10 %		25	55	μA
	I _{DD5}	XT1 = V _{DD} STOP mode When feedback resistor is connected	V _{DD} = 5.0 V ± 10 %		25	55	μA
			V _{DD} = 3.0 V ± 10 %		5	15	μA
			V _{DD} = 2.2 V ± 10 %		2.5	12.5	μA
I _{DD6}	XT1 = V _{DD} STOP mode When feedback resistor is disconnected	V _{DD} = 5.0 V ± 10 %		1	30	μA	
		V _{DD} = 3.0 V ± 10 %		0.5	10	μA	
		V _{DD} = 2.2 V ± 10 %		0.3	10	μA	
I _{DD6}	XT1 = V _{DD} STOP mode When feedback resistor is disconnected	V _{DD} = 5.0 V ± 10 %		0.1	30	μA	
		V _{DD} = 3.0 V ± 10 %		0.05	10	μA	
		V _{DD} = 2.2 V ± 10 %		0.05	10	μA	

- Notes**
1. Current flowing V_{DD} pin. Not including A/D converter, ports, on-chip pull-up resistors or LCD dividing resistors.
 2. Main system clock f_{xx} = f_x/2 operation (when oscillation mode selection register (OSMS) is set to 00H)
 3. Main system clock f_{xx} = f_x operation (when OSMS is set to 01H)
 4. When the main system clock is stopped.
 5. High-speed mode operation (when processor clock control register (PCC) is set to 00H)
 6. Low-speed mode operation (when PCC is set to 04H)

Remark Unless specified otherwise, the characteristics of dual-function pins are the same as the those of port pins.

LCD CONTROLLER/DRIVER CHARACTERISTICS (AT NORMAL OPERATION)

(1) Static Display Mode (T_A = -10 to +85 °C, V_{DD} = 2.0 to 5.5 V)

Parameter	Symbol	Test Conditions		MIN.	TYP.	MAX.	Unit
LCD drive voltage	V _{LCD}			2.0		V _{DD}	V
LCD dividing resistor	R _{LCD}			60	100	150	kΩ
LCD output voltage deviation ^{Note} (common)	V _{ODC}	I _o = ±5 μA	V _{LCD0} = V _{LCD}	0		±0.2	V
LCD output voltage deviation ^{Note} (segment)	V _{ODS}	I _o = ±1 μA		0		±0.2	V

Note The voltage deviation is the difference from the output voltage corresponding to the ideal value of the segment and common outputs (V_{LCDn}; n = 0, 1, 2).

(2) 1/3 Bias Method (T_A = -10 to +85 °C, V_{DD} = 2.5 to 5.5 V)

Parameter	Symbol	Test Conditions		MIN.	TYP.	MAX.	Unit
LCD drive voltage	V _{LCD}			2.5		V _{DD}	V
LCD dividing resistor	R _{LCD}			60	100	150	kΩ
LCD output voltage deviation ^{Note} (common)	V _{ODC}	I _o = ±5 μA	V _{LCD0} = V _{LCD} V _{LCD1} = V _{LCD} × 2/3 V _{LCD2} = V _{LCD} × 1/3	0		±0.2	V
LCD output voltage deviation ^{Note} (segment)	V _{ODS}	I _o = ±1 μA		0		±0.2	V

Note The voltage deviation is the difference from the output voltage corresponding to the ideal value of the segment and common outputs (V_{LCDn}; n = 0, 1, 2).

(3) 1/2 Bias Method (T_A = -10 to +85 °C, V_{DD} = 2.7 to 5.5 V)

Parameter	Symbol	Test Conditions		MIN.	TYP.	MAX.	Unit
LCD drive voltage	V _{LCD}			2.7		V _{DD}	V
LCD dividing resistor	R _{LCD}			60	100	150	kΩ
LCD output voltage deviation ^{Note} (common)	V _{ODC}	I _o = ±5 μA	V _{LCD0} = V _{LCD} V _{LCD1} = V _{LCD} × 1/2 V _{LCD2} = V _{LCD1}	0		±0.2	V
LCD output voltage deviation ^{Note} (segment)	V _{ODS}	I _o = ±1 μA		0		±0.2	V

Note The voltage deviation is the difference from the output voltage corresponding to the ideal value of the segment and common outputs (V_{LCDn}; n = 0, 1, 2).

LCD CONTROLLER/DRIVER CHARACTERISTICS (AT LOW-VOLTAGE OPERATION)

★ (1) Static Display Mode (T_A = -10 to +85 °C, 2.0 V ≤ V_{DD} < 3.4 V)

Parameter	Symbol	Test Conditions		MIN.	TYP.	MAX.	Unit
LCD drive voltage	V _{LCD}			2.0		V _{DD}	V
LCD dividing resistor	R _{LCD}			60	100	150	kΩ
LCD output voltage deviation ^{Note} (common)	V _{ODC}	I _o = ±5 μA	V _{LCD0} = V _{LCD}	0		±0.2	V
LCD output voltage deviation ^{Note} (segment)	V _{ODS}	I _o = ±1 μA		0		±0.2	V

Note The voltage deviation is the difference from the output voltage corresponding to the ideal value of the segment and common outputs (V_{LCDn}; n = 0, 1, 2).

★ (2) 1/3 Bias Method (T_A = -10 to +85 °C, 2.0 V ≤ V_{DD} < 3.4 V)

Parameter	Symbol	Test Conditions		MIN.	TYP.	MAX.	Unit
LCD drive voltage	V _{LCD}			2.0		V _{DD}	V
LCD dividing resistor	R _{LCD}			60	100	150	kΩ
LCD output voltage deviation ^{Note} (common)	V _{ODC}	I _o = ±5 μA	V _{LCD0} = V _{LCD} V _{LCD1} = V _{LCD} × 2/3 V _{LCD2} = V _{LCD} × 1/3	0		±0.2	V
LCD output voltage deviation ^{Note} (segment)	V _{ODS}	I _o = ±1 μA		0		±0.2	V

Note The voltage deviation is the difference from the output voltage corresponding to the ideal value of the segment and common outputs (V_{LCDn}; n = 0, 1, 2).

★ (3) 1/2 Bias Method (T_A = -10 to +85 °C, 2.0 V ≤ V_{DD} < 3.4 V)

Parameter	Symbol	Test Conditions		MIN.	TYP.	MAX.	Unit
LCD drive voltage	V _{LCD}			2.0		V _{DD}	V
LCD dividing resistor	R _{LCD}			60	100	150	kΩ
LCD output voltage deviation ^{Note} (common)	V _{ODC}	I _o = ±5 μA	V _{LCD0} = V _{LCD} V _{LCD1} = V _{LCD} × 1/2 V _{LCD2} = V _{LCD1}	0		±0.2	V
LCD output voltage deviation ^{Note} (segment)	V _{ODS}	I _o = ±1 μA		0		±0.2	V

Note The voltage deviation is the difference from the output voltage corresponding to the ideal value of the segment and common outputs (V_{LCDn}; n = 0, 1, 2).

AC CHARACTERISTICS

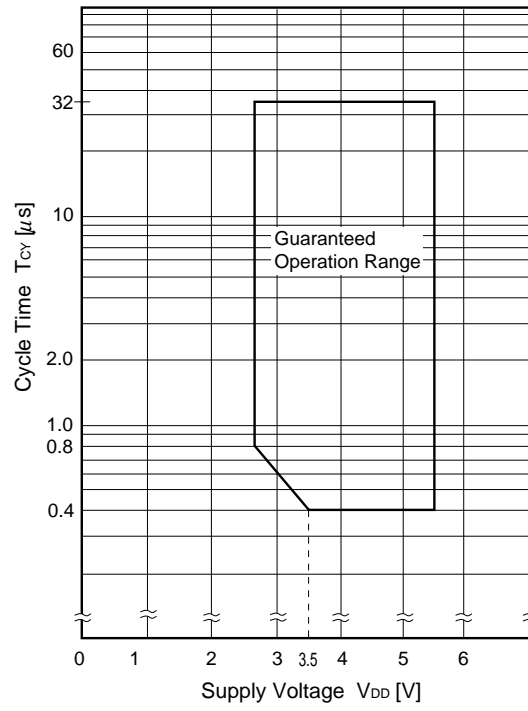
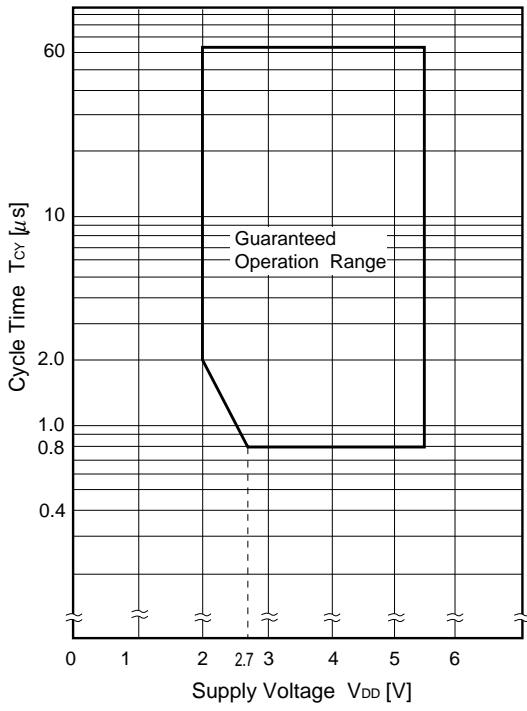
(1) Basic Operation (T_A = -40 to +85 °C, V_{DD} = 2.0 to 5.5 V)

Parameter	Symbol	Test Conditions		MIN.	TYP.	MAX.	Unit
Cycle time (Min. instruction execution time)	T _{CY}	Operating on main system clock (f _{XX} = 2.5 MHz) ^{Note 1}	V _{DD} = 2.7 to 5.5 V	0.8		64	μs
				2.0		64	μs
		Operating on main system clock (f _{XX} = 5.0 MHz) ^{Note 2}	3.5 ≤ V _{DD} ≤ 5.5 V	0.4		32	μs
			2.7 ≤ V _{DD} < 3.5 V	0.8		32	μs
		Operating on subsystem clock		40 ^{Note 3}	122	125	μs
T100 input frequency	f _{T100}	f _{T100} = t _{TIH00} + t _{TIL00}		0		1/t _{T100}	MHz
T100 input high/ low-level width	t _{TIH00} ,	3.5 V ≤ V _{DD} ≤ 5.5 V		2/f _{SSAM} +0.1 ^{Note 4}			μs
	t _{TIL00}	2.7 V ≤ V _{DD} < 3.5 V		2/f _{SSAM} +0.2 ^{Note 4}			μs
		2.0 V ≤ V _{DD} < 2.7 V		2/f _{SSAM} +0.5 ^{Note 4}			μs
T101 input frequency	f _{T101}	V _{DD} = 2.7 to 5.5 V		0		100	kHz
				0		50	kHz
T101 input high/ low-level width	t _{TIH01} ,	V _{DD} = 2.7 to 5.5 V		10			μs
	t _{TIL01}			20			μs
T11, T12 input frequency	f _{T11}	V _{DD} = 4.5 to 5.5 V		0		4	MHz
				0		275	kHz
T11, T12 input high/low-level width	t _{TIH} ,	V _{DD} = 4.5 to 5.5 V		100			ns
	t _{TIL}			1.8			μs
Interrupt request input high/low- level width	t _{INTH} ,	INTP0	3.5 V ≤ V _{DD} ≤ 5.5 V	2/f _{SSAM} +0.1 ^{Note 4}			μs
	t _{INTH} ,		2.7 V ≤ V _{DD} < 3.5 V	2/f _{SSAM} +0.2 ^{Note 4}			μs
	t _{INTH} ,		2.0 V ≤ V _{DD} < 2.7 V	2/f _{SSAM} +0.5 ^{Note 4}			μs
	t _{INTL}	INTP1-INTP5, P110-P117	V _{DD} = 2.7 to 5.5 V	10			μs
				20			μs
RESET low level width	t _{RST}	V _{DD} = 2.7 to 5.5 V		10			μs
				20			μs

- Notes**
1. Main system clock f_{XX} = f_X/2 operation (when oscillation mode selection register (OSMS) is set to 00H)
 2. Main system clock f_{XX} = f_X operation (when OSMS is set to 01H)
 3. This is the value when the external clock is used. The value is 114 μs (min.) when the crystal resonator is used.
 4. In combination with bits 0 (SCS0) and 1 (SCS1) of sampling clock select register (SCS), selection of f_{SSAM} is possible between f_{XX}/2^{N+1}, f_{XX}/32, f_{XX}/64 and f_{XX}/128 (when N = 0 to 4).

T_{CY} vs V_{DD} (At main system clock f_{xx} = f_x/2 operation)

★ T_{CY} vs V_{DD} (At main system clock f_{xx} = f_x operation)



(2) Serial Interface (T_A = -40 to +85 °C, V_{DD} = 2.0 to 5.5 V)

(a) Serial interface channel 0

(i) 3-wire serial I/O mode ($\overline{\text{SCK0}}$... Internal clock output)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
$\overline{\text{SCK0}}$ cycle time	t _{KCY1}	4.5 V ≤ V _{DD} ≤ 5.5 V	800			ns
		2.7 V ≤ V _{DD} < 4.5 V	1600			ns
			3200			ns
$\overline{\text{SCK0}}$ high/low-level width	t _{KH1} ,	V _{DD} = 4.5 to 5.5 V	t _{KCY1} /2-50			ns
	t _{KL1}		t _{KCY1} /2-100			ns
SI0 setup time (to $\overline{\text{SCK0}}\uparrow$)	t _{SIK1}	4.5 V ≤ V _{DD} ≤ 5.5 V	100			ns
		2.7 V ≤ V _{DD} < 4.5 V	150			ns
			300			ns
SI0 hold time (from $\overline{\text{SCK0}}\uparrow$)	t _{KSI1}		400			ns
SO0 output delay time from $\overline{\text{SCK0}}\downarrow$	t _{KSO1}	C = 100 pF ^{Note}			300	ns

Note C is the load capacitance of $\overline{\text{SCK0}}$, SO0 output line.

(ii) 3-wire serial I/O mode ($\overline{\text{SCK0}}$...External clock input)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
$\overline{\text{SCK0}}$ cycle time	t _{KCY2}	4.5 V ≤ V _{DD} ≤ 5.5 V	800			ns
		2.7 V ≤ V _{DD} < 4.5 V	1600			ns
			3200			ns
$\overline{\text{SCK0}}$ high/low-level width	t _{KH2} , t _{KL2}	4.5 V ≤ V _{DD} ≤ 5.5 V	400			ns
		2.7 V ≤ V _{DD} < 4.5 V	800			ns
			1600			ns
SI0 setup time (to $\overline{\text{SCK0}}\uparrow$)	t _{SIK2}		100			ns
SI0 hold time (from $\overline{\text{SCK0}}\uparrow$)	t _{KSI2}		400			ns
SO0 output delay time from $\overline{\text{SCK0}}\downarrow$	t _{KSO2}	C = 100 pF ^{Note}			300	ns
$\overline{\text{SCK0}}$ rise, fall time	t _{R2} , t _{F2}				1000	ns

Note C is the load capacitance of SO0 output line.

(iii) 2-wire serial I/O mode ($\overline{\text{SCK0}}$... Internal clock output)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit	
$\overline{\text{SCK0}}$ cycle time	t_{KCY3}	R = 1 kΩ, C = 100 pF ^{Note}	V _{DD} = 2.7 to 5.5 V	1600			ns
				3200			ns
$\overline{\text{SCK0}}$ high-level width	t_{KH3}		V _{DD} = 2.7 to 5.5 V	$t_{\text{KCY3}}/2-160$			ns
				$t_{\text{KCY3}}/2-190$			ns
$\overline{\text{SCK0}}$ low-level width	t_{KL3}		V _{DD} = 4.5 to 5.5 V	$t_{\text{KCY3}}/2-50$			ns
				$t_{\text{KCY3}}/2-100$			ns
SB0, SB1 setup time (to $\overline{\text{SCK0}}\uparrow$)	t_{SIK3}		4.5 V ≤ V _{DD} ≤ 5.5 V	300			ns
			2.7 V ≤ V _{DD} < 4.5 V	350			ns
				400			ns
SB0, SB1 hold time (from $\overline{\text{SCK0}}\uparrow$)	t_{KSI3}			600			ns
SB0, SB1 output delay time from $\overline{\text{SCK0}}\downarrow$	t_{KSO3}				300	ns	

Note R and C are the load resistance and load capacitance of the $\overline{\text{SCK0}}$, SB0 and SB1 output line.

(iv) 2-wire serial I/O mode ($\overline{\text{SCK0}}$... External clock input)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit	
$\overline{\text{SCK0}}$ cycle time	t_{KCY4}	V _{DD} = 2.7 to 5.5 V	1600			ns	
			3200			ns	
$\overline{\text{SCK0}}$ high-level width	t_{KH4}	V _{DD} = 2.7 to 5.5 V	650			ns	
			1300			ns	
$\overline{\text{SCK0}}$ low-level width	t_{KL4}	V _{DD} = 2.7 to 5.5 V	800			ns	
			1600			ns	
SB0, SB1 setup time (to $\overline{\text{SCK0}}\uparrow$)	t_{SIK4}		100			ns	
SB0, SB1 hold time (from $\overline{\text{SCK0}}\uparrow$)	t_{KSI4}		$t_{\text{KCY4}}/2$			ns	
SB0, SB1 output delay time from $\overline{\text{SCK0}}\downarrow$	t_{KSO4}	R = 1 kΩ, C = 100 pF ^{Note}	V _{DD} = 4.5 to 5.5 V	0		300	ns
				0		500	ns
$\overline{\text{SCK0}}$ rise, fall time	$t_{\text{R4}},$ t_{F4}				1000	ns	

Note R and C are the load resistance and load capacitance of the SB0 and SB1 output line.

(v) I²C bus mode (SCL...Internal clock output)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit									
SCL cycle time	t _{KCY5}	R = 1 kΩ , C = 100 pF ^{Note}	V _{DD} = 2.7 to 5.5 V	10			μs								
				20			μs								
SCL high-level width	t _{KH5}		R = 1 kΩ , C = 100 pF ^{Note}	V _{DD} = 2.7 to 5.5 V	t _{KCY5} -160			ns							
					t _{KCY5} -190			ns							
SCL low-level width	t _{KL5}			R = 1 kΩ , C = 100 pF ^{Note}	V _{DD} = 4.5 to 5.5 V	t _{KCY5} -50			ns						
						t _{KCY5} -100			ns						
SDA0, SDA1 setup time (to SCL↑)	t _{SIK5}				R = 1 kΩ , C = 100 pF ^{Note}	V _{DD} = 2.7 to 5.5 V	200			ns					
							300			ns					
SDA0, SDA1 hold time (to SCL↓)	t _{KSI5}					R = 1 kΩ , C = 100 pF ^{Note}		0			ns				
SDA0, SDA1 output delay time (from SCL↓)	t _{KSO5}							R = 1 kΩ , C = 100 pF ^{Note}	V _{DD} = 4.5 to 5.5 V	0		300	ns		
										0		500	ns		
SDA0, SDA1↓ from SCL↑ or SDA0, SDA1↑ from SCL↑	t _{KSB}	R = 1 kΩ , C = 100 pF ^{Note}								200			ns		
SCL↓ from SDA0, SDA1↓	t _{SBK}		R = 1 kΩ , C = 100 pF ^{Note}								400			ns	
SDA0, SDA1 high-level width	t _{SBH}			R = 1 kΩ , C = 100 pF ^{Note}								500			ns

Note R and C are the load resistance and load capacitance of SCL, SDA0, and SDA1 output line.

(vi) I²C bus mode (SCL...External clock output)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit	
SCL cycle time	t _{KCY6}		1000			ns	
SCL high/low-level width	t _{KH5} , t _{KL6}		400			ns	
SDA0, SDA1 setup time (to SCL↑)	t _{SIK6}		200			ns	
SDA0, SDA1 hold time (to SCL↓)	t _{KSI6}		0			ns	
SDA0, SDA1 output delay time (from SCL↓)	t _{KSO6}	R = 1 kΩ , C = 100 pF ^{Note}	V _{DD} = 4.5 to 5.5 V	0		300	ns
				0		500	ns
SDA0, SDA1↓ from SCL↑ or SDA0, SDA1↑ from SCL↑	t _{KSB}		200			ns	
SCL↓ from SDA0, SDA1↓	t _{SBK}		400			ns	
SDA0, SDA1 high-level width	t _{SBH}		500			ns	
SCL rise, fall time	t _{r6} , t _{f6}				1000	ns	

Note R and C are the load resistance and load capacitance of SCL, SDA0, and SDA1 output line.

(b) Serial interface channel 2

(i) 3-wire serial I/O mode ($\overline{\text{SCK2}}$... Internal clock output)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
$\overline{\text{SCK2}}$ cycle time	t_{KCY7}	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	800			ns
		$2.7 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	1600			ns
			3200			ns
$\overline{\text{SCK2}}$ high/low-level width	$t_{\text{KH7}},$	$V_{\text{DD}} = 4.5 \text{ to } 5.5 \text{ V}$	$t_{\text{KCY7}}/2-50$			ns
	t_{KL7}		$t_{\text{KCY7}}/2-100$			ns
SI2 setup time (to $\overline{\text{SCK2}}\uparrow$)	t_{SIK7}	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	100			ns
		$2.7 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	150			ns
			300			ns
SI2 hold time (from $\overline{\text{SCK2}}\uparrow$)	t_{KSI7}		400			ns
SO2 output delay time from $\overline{\text{SCK2}}\downarrow$	t_{KSO1}	$C = 100 \text{ pF}^{\text{Note}}$			300	ns

Note C is the load capacitance of $\overline{\text{SCK2}}$, SO2 output line.

(ii) 3-wire serial I/O mode ($\overline{\text{SCK2}}$...External clock input)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
$\overline{\text{SCK2}}$ cycle time	t_{KCY8}	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	800			ns
		$2.7 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	1600			ns
			3200			ns
$\overline{\text{SCK2}}$ high/low-level width	$t_{\text{KH8}},$	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	400			ns
		$2.7 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	800			ns
			1600			ns
SI2 setup time (to $\overline{\text{SCK2}}\uparrow$)	t_{SIK8}		100			ns
SI2 hold time (from $\overline{\text{SCK2}}\uparrow$)	t_{KSI8}		400			ns
SO2 output delay time from $\overline{\text{SCK2}}\downarrow$	t_{KSO8}	$C = 100 \text{ pF}^{\text{Note}}$			300	ns
$\overline{\text{SCK2}}$ rise, fall time	$t_{\text{R8}},$ t_{F8}				1000	ns

Note C is the load capacitance of SO2 output line.

(iii) UART mode (Dedicated baud rate generator output)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate		$4.5\text{ V} \leq V_{DD} \leq 5.5\text{ V}$			78125	bps
		$2.7\text{ V} \leq V_{DD} < 4.5\text{ V}$			39063	bps
					19531	bps

(iv) UART mode (External clock input)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
ASCK cycle time	t_{KCY9}	$4.5\text{ V} \leq V_{DD} \leq 5.5\text{ V}$	800			ns
		$2.7\text{ V} \leq V_{DD} < 4.5\text{ V}$	1600			ns
			3200			ns
ASCK high/low-level width	$t_{KH9},$ t_{KL9}	$4.5\text{ V} \leq V_{DD} \leq 5.5\text{ V}$	400			ns
		$2.7\text{ V} \leq V_{DD} < 4.5\text{ V}$	800			ns
			1600			ns
Transfer rate		$4.5\text{ V} \leq V_{DD} \leq 5.5\text{ V}$			39063	bps
		$2.7\text{ V} \leq V_{DD} < 4.5\text{ V}$			19531	bps
					9766	bps
ASCK rise, fall time	$t_{R9},$ t_{F9}				1000	ns

(c) Serial interface channel 3

(i) 3-wire serial I/O mode ($\overline{\text{SCK3}}$... Internal clock output)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
$\overline{\text{SCK3}}$ cycle time	t_{KCY10}	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	800			ns
		$2.7 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	1600			ns
			3200			ns
$\overline{\text{SCK3}}$ high/low-level width	$t_{\text{KH10}},$ t_{KL10}	$V_{\text{DD}} = 4.5 \text{ to } 5.5 \text{ V}$	$t_{\text{KCY10}}/2-50$			ns
			$t_{\text{KCY10}}/2-100$			ns
SI3 setup time (to $\overline{\text{SCK3}}\uparrow$)	t_{SIK10}	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	100			ns
		$2.7 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	150			ns
			300			ns
SI3 hold time (from $\overline{\text{SCK3}}\uparrow$)	t_{KSI10}		400			ns
SO3 output delay time from $\overline{\text{SCK3}}\downarrow$	t_{KSO10}	$C = 100 \text{ pF}^{\text{Note}}$			300	ns

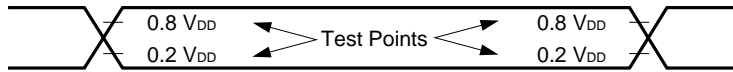
Note C is the load capacitance of $\overline{\text{SCK3}}$, SO3 output line.

(ii) 3-wire serial I/O mode ($\overline{\text{SCK3}}$...External clock input)

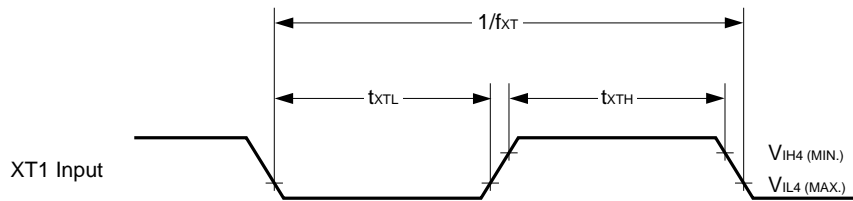
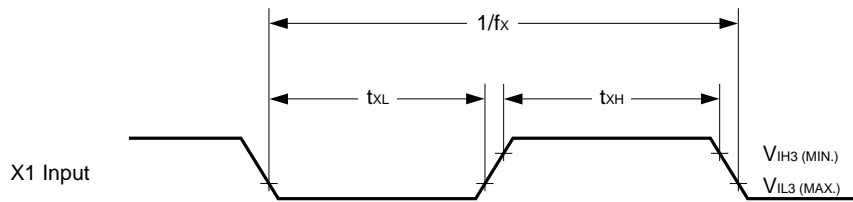
Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
$\overline{\text{SCK3}}$ cycle time	t_{KCY11}	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	800			ns
		$2.7 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	1600			ns
			3200			ns
$\overline{\text{SCK3}}$ high/low-level width	$t_{\text{KH11}},$ t_{KL11}	$4.5 \text{ V} \leq V_{\text{DD}} \leq 5.5 \text{ V}$	400			ns
		$2.7 \text{ V} \leq V_{\text{DD}} < 4.5 \text{ V}$	800			ns
			1600			ns
SI3 setup time (to $\overline{\text{SCK3}}\uparrow$)	t_{SIK11}		100			ns
SI3 hold time (from $\overline{\text{SCK3}}\uparrow$)	t_{KSI11}		400			ns
SO3 output delay time from $\overline{\text{SCK3}}\downarrow$	t_{KSO11}	$C = 100 \text{ pF}^{\text{Note}}$			300	ns
$\overline{\text{SCK3}}$ rise, fall time	$t_{\text{R11}},$ t_{F11}				1000	ns

Note C is the load capacitance of SO3 output line.

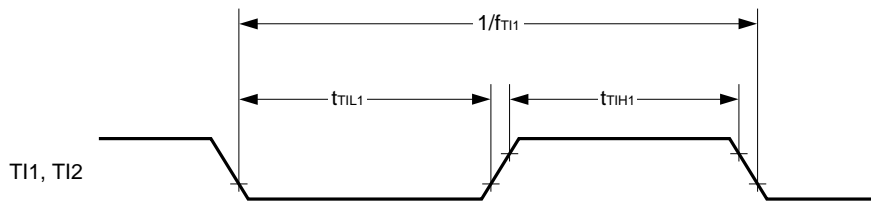
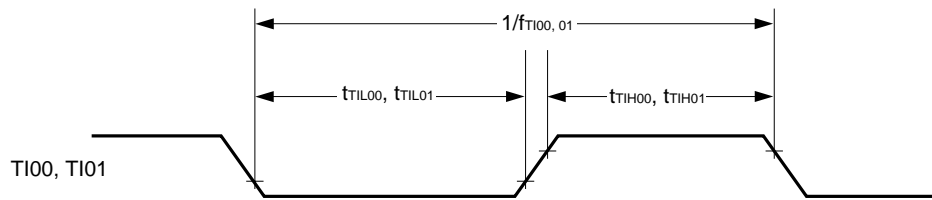
AC Timing Test Point (Excluding X1, XT1 Input)



Clock Timing

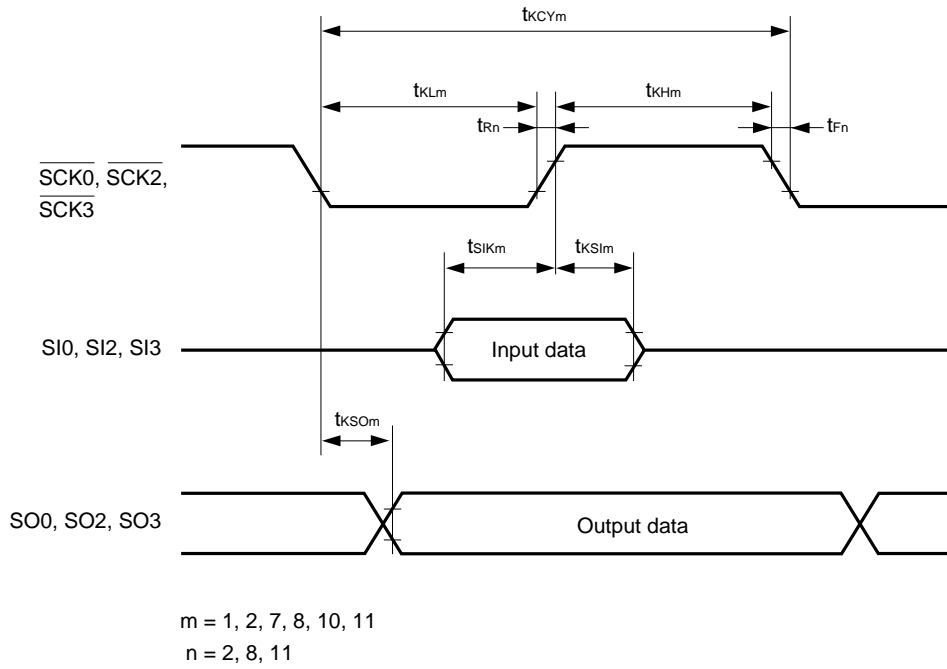


TI Timing

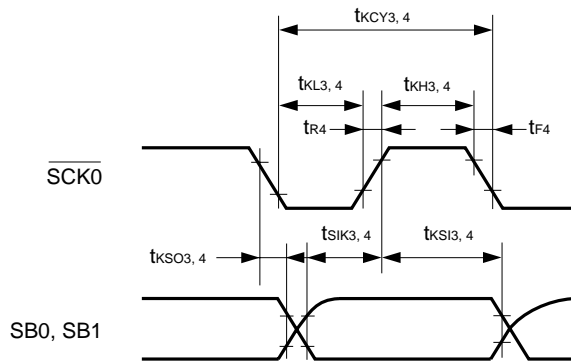


Serial Transfer Timing

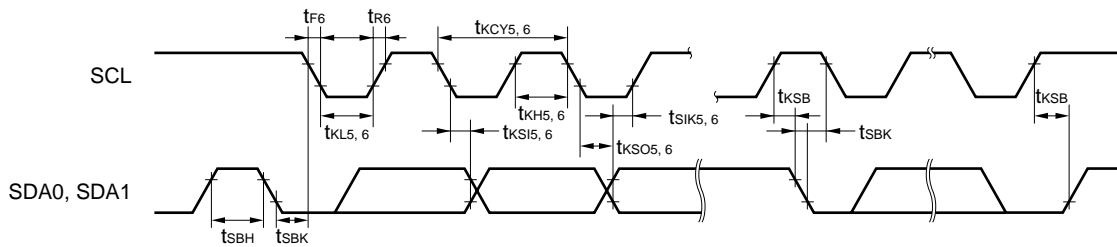
3-wire serial I/O mode:



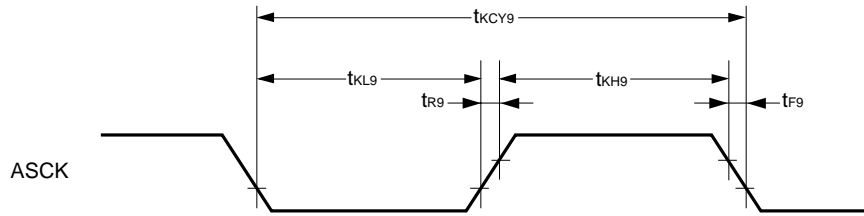
2-wire serial I/O mode:



I²C bus mode:



UART mode:



A/D Converter ($T_A = -40$ to $+85$ °C, $AV_{DD} = V_{DD} = 2.0$ to 5.5 V, $AV_{SS} = V_{SS} = 0$ V)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
Resolution			8	8	8	bit
Overall error ^{Note 1}		$2.7\text{ V} \leq AV_{REF} \leq 5.5$			± 0.6	%
		$2.0\text{ V} \leq AV_{REF} < 2.7\text{ V}$			± 1.4	%
Conversion time	t_{CONV}		19.1		200	μs
Sampling time	t_{SAMP}		$12/f_{XX}$			μs
Analog input voltage	V_{IAN}		AV_{SS}		AV_{REF}	V
Reference voltage	AV_{REF}		2.0		AV_{DD}	V
AV_{REF} - AV_{SS} resistance	R_{REF}	When not operating A/D conversion	4	14		$\text{k}\Omega$
AV_{REF} current	AI_{REF}	When operating A/D conversion ^{Note 2}		2.5	5.0	mA
		When not operating A/D conversion ^{Note 3}		0.5	1.5	mA

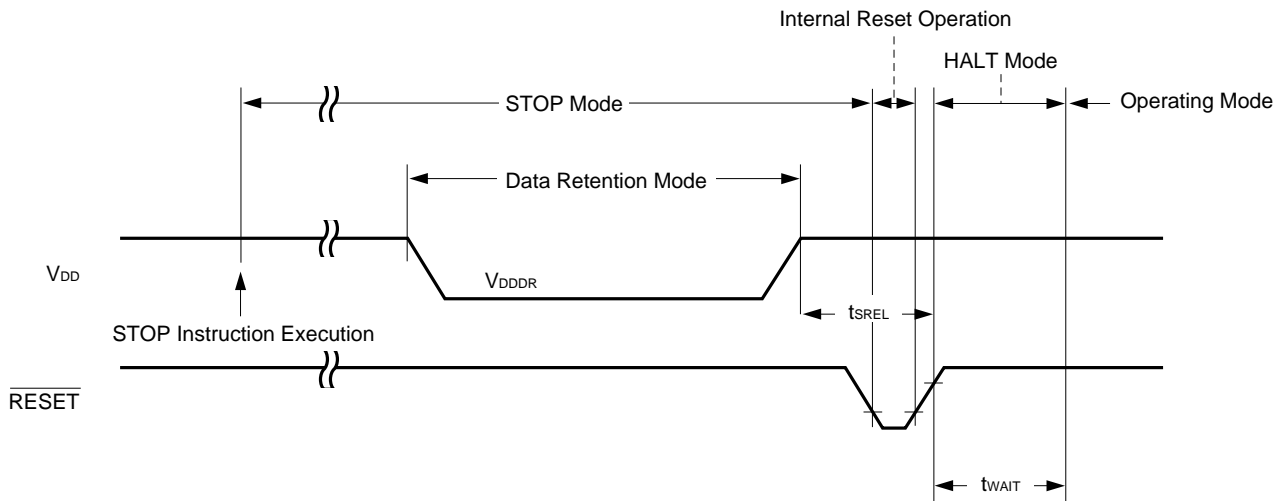
- Notes**
1. Quantization error ($\pm 1/2$ LSB) is not included. This is expressed in proportion to the full-scale value.
 2. Indicates current flowing to AV_{REF} pin when the CS bit of the A/D converter mode register (ADM) is 1.
 3. Indicates current flowing to AV_{REF} pin when the CS bit of the ADM is 0.

DATA MEMORY STOP MODE LOW SUPPLY VOLTAGE DATA RETENTION CHARACTERISTICS (T_A = -40 to +85 °C)

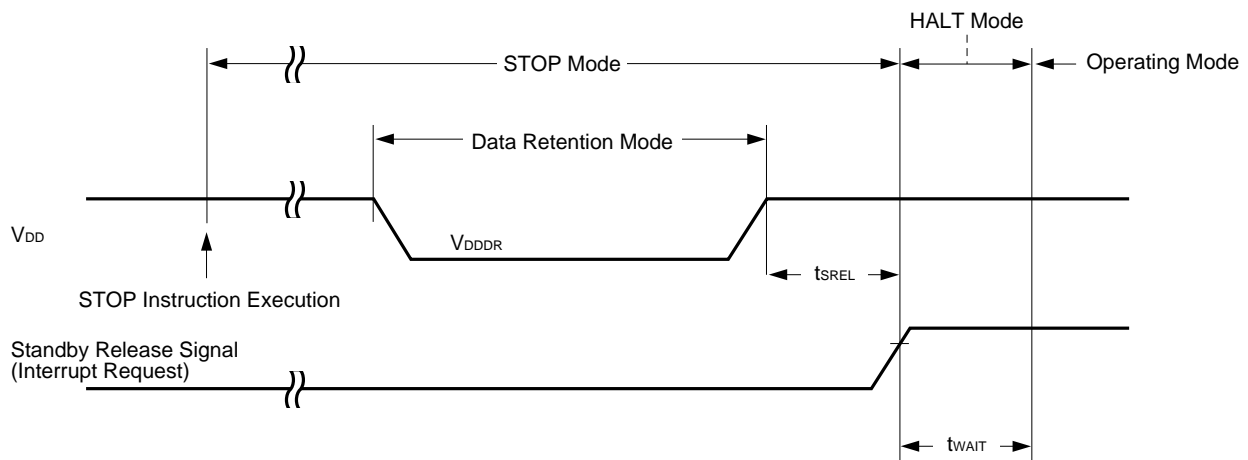
Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	V _{DDDR}		1.6		5.5	V
Data retention power supply current	I _{DDDR}	V _{DDDR} = 1.6 V Subsystem clock stop and feed-back resistor disconnected		0.1	10	μA
Release signal set time	t _{SREL}		0			μs
Oscillation stabilization wait time	t _{WAIT}	Release by $\overline{\text{RESET}}$		2 ¹⁷ /f _x		ms
		Release by interrupt		Note		ms

Note In combination with bits 0 to 2 (OSTS0 to OSTS2) of oscillation stabilization time select register (OSTS), selection of 2¹²/f_{xx} and 2¹⁴/f_{xx} to 2¹⁷/f_{xx} is possible.

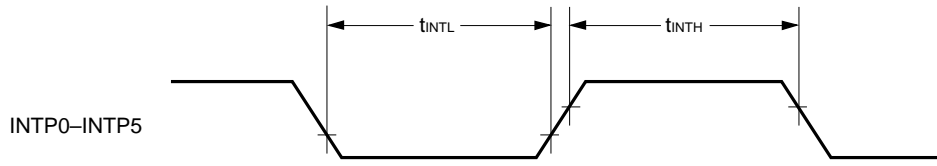
Data Retention Timing (STOP Mode Release by $\overline{\text{RESET}}$)



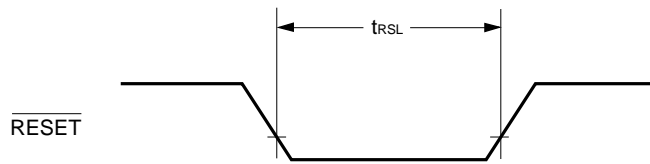
Data Retention Timing (Standby Release Signal: STOP Mode Release by Interrupt Signal)



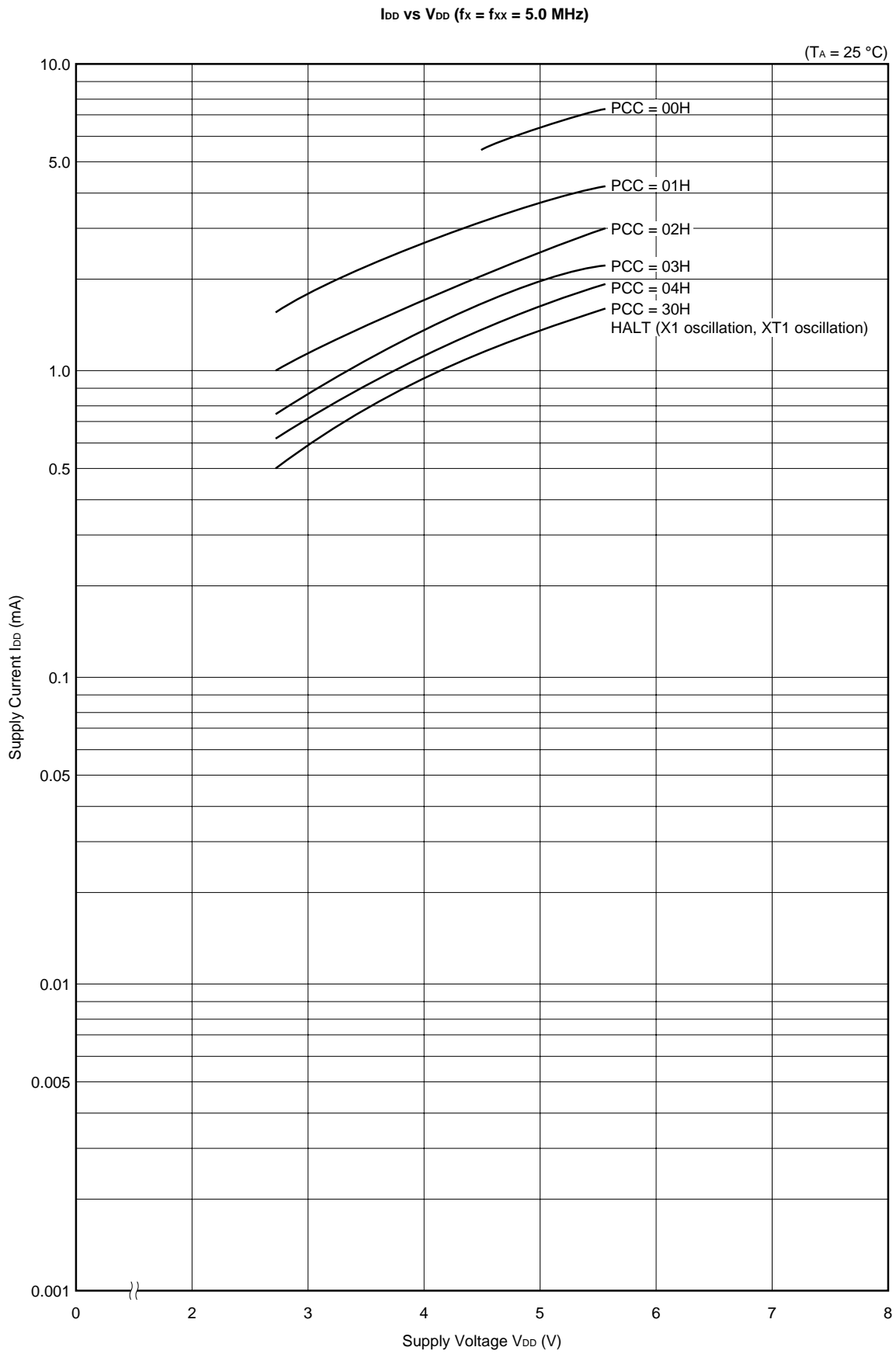
Interrupt Request Input Timing



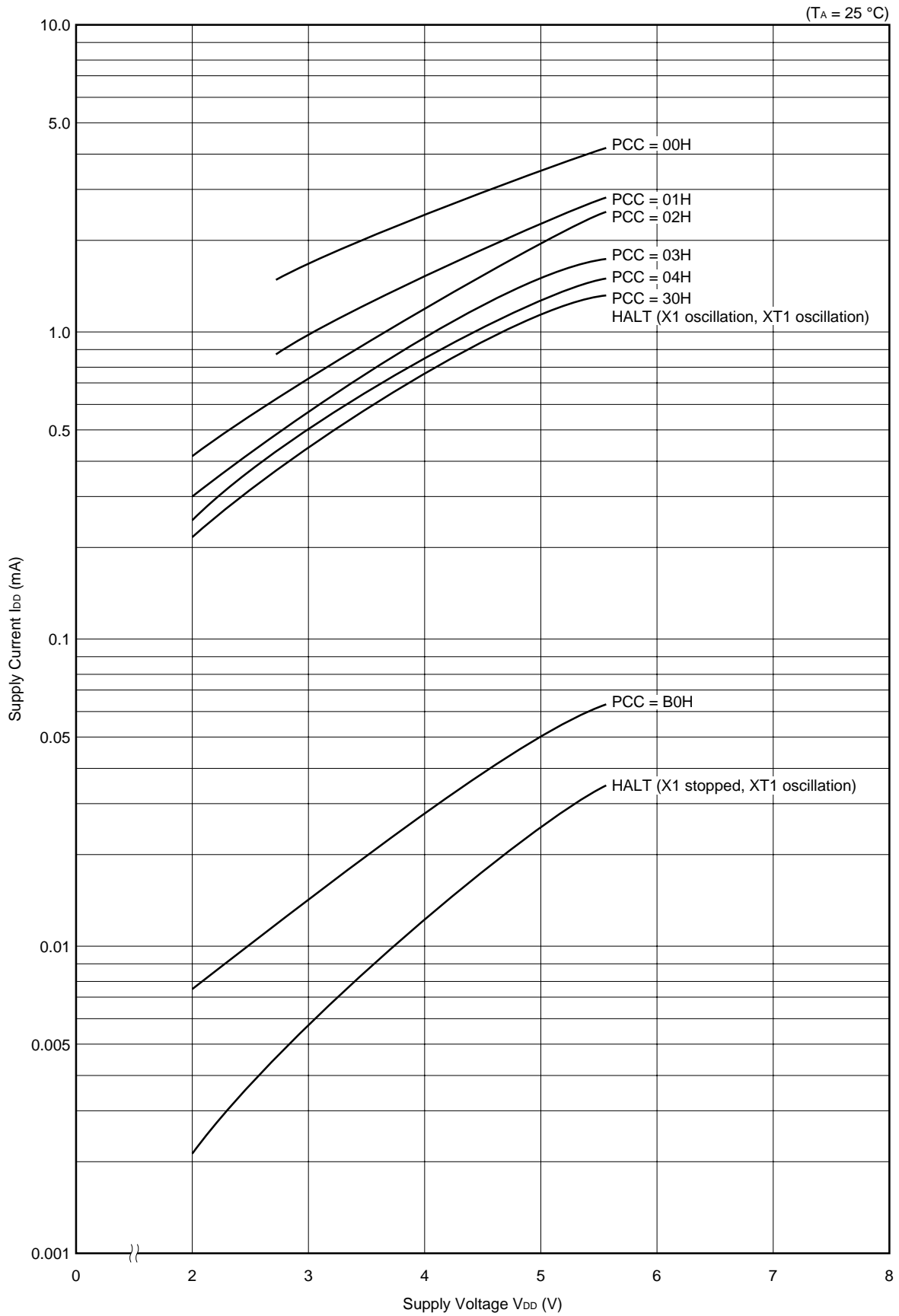
$\overline{\text{RESET}}$ Input Timing



11. CHARACTERISTICS CURVE (REFERENCE VALUE)

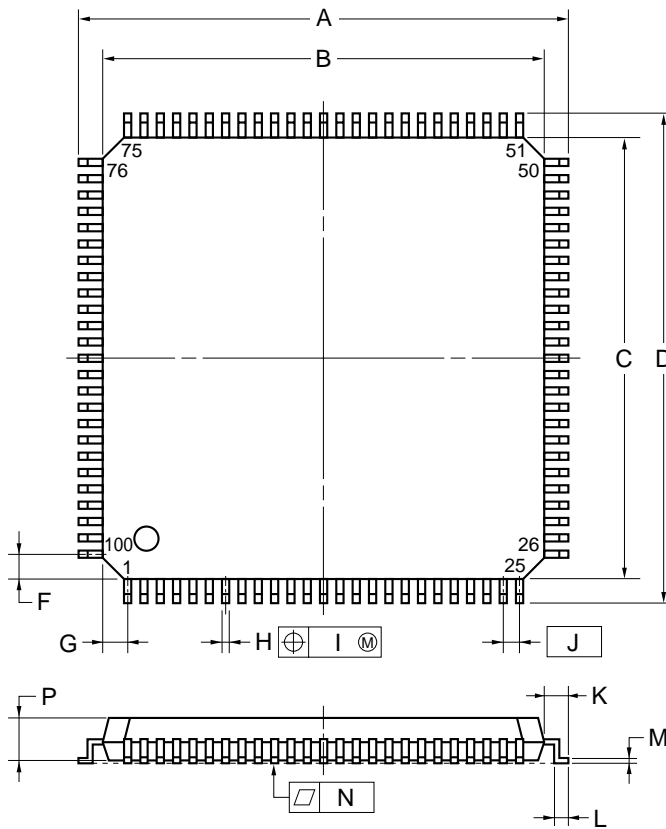


I_{DD} vs V_{DD} (f_x = 5.0 MHz, f_{xx} = 2.5 MHz)

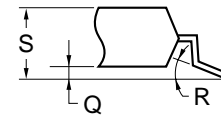


12. PACKAGE DRAWINGS

100 PIN PLASTIC LQFP (FINE PITCH) (14×14)



detail of lead end



NOTE

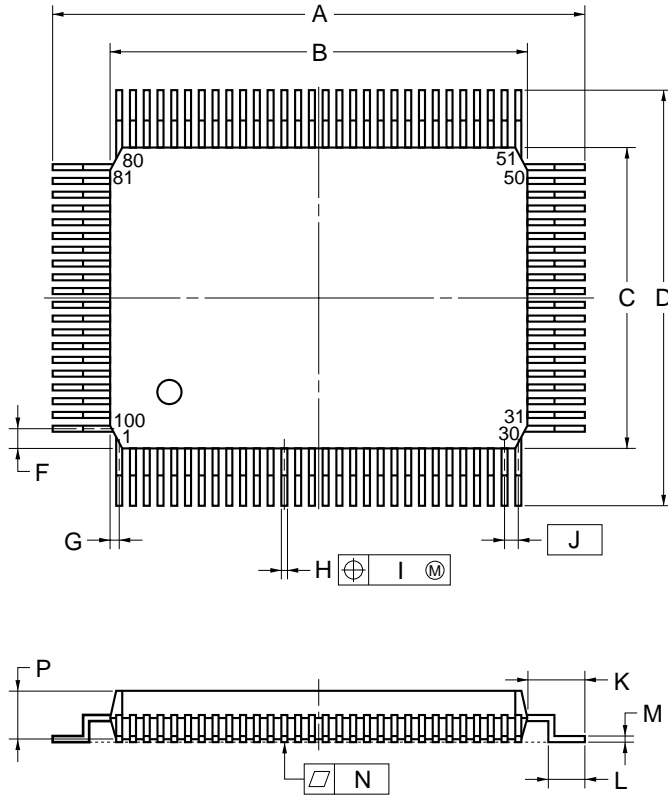
Each lead centerline is located within 0.08 mm (0.003 inch) of its true position (T.P.) at maximum material condition.

ITEM	MILLIMETERS	INCHES
A	16.00±0.20	0.630±0.008
B	14.00±0.20	0.551 ^{+0.009} _{-0.008}
C	14.00±0.20	0.551 ^{+0.009} _{-0.008}
D	16.00±0.20	0.630±0.008
F	1.00	0.039
G	1.00	0.039
H	0.22 ^{+0.05} _{-0.04}	0.009±0.002
I	0.08	0.003
J	0.50 (T.P.)	0.020 (T.P.)
K	1.00±0.20	0.039 ^{+0.009} _{-0.008}
L	0.50±0.20	0.020 ^{+0.008} _{-0.009}
M	0.17 ^{+0.03} _{-0.07}	0.007 ^{+0.001} _{-0.003}
N	0.08	0.003
P	1.40±0.05	0.055±0.002
Q	0.10±0.05	0.004±0.002
R	3° ^{+7°} _{-3°}	3° ^{+7°} _{-3°}
S	1.60 MAX.	0.063 MAX.

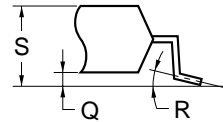
S100GC-50-8EU

Remark Dimensions and materials of ES products are the same as those of the mass production product.

100PIN PLASTIC QFP (14x20)



detail of lead end



NOTE

Each lead centerline is located within 0.15 mm (0.006 inch) of its true position (T.P.) at maximum material condition.

ITEM	MILLIMETERS	INCHES
A	23.6±0.4	0.929±0.016
B	20.0±0.2	0.795 ^{+0.009} _{-0.008}
C	14.0±0.2	0.551 ^{+0.009} _{-0.008}
D	17.6±0.4	0.693±0.016
F	0.8	0.031
G	0.6	0.024
H	0.30±0.10	0.012 ^{+0.004} _{-0.005}
I	0.15	0.006
J	0.65 (T.P.)	0.026 (T.P.)
K	1.8±0.2	0.071 ^{+0.008} _{-0.009}
L	0.8±0.2	0.031 ^{+0.009} _{-0.008}
M	0.15 ^{+0.10} _{-0.05}	0.006 ^{+0.004} _{-0.003}
N	0.10	0.004
P	2.7±0.1	0.106 ^{+0.005} _{-0.004}
Q	0.1±0.1	0.004±0.004
R	5°±5°	5°±5°
S	3.0 MAX.	0.119 MAX.

P100GF-65-3BA1-3

Remark Dimensions and materials of ES products are the same as those of the mass production product.

13. RECOMMENDED SOLDERING CONDITIONS

The μPD780306Y and 780308Y should be soldered and mounted under the conditions recommended in the table below.

For detail of recommended soldering conditions, refer to the information document **Semiconductor Device Mounting Technology Manual (C10535E)**.

For soldering methods and conditions other than those recommended below, contact our sales personnel.

Table 13-1. Surface Mounting Type Soldering Conditions

(1) μPD780306YGF-xxx-3BA: 100-pin plastic QFP (14 × 20 mm)

μPD780308YGF-xxx-3BA: 100-pin plastic QFP (14 × 20 mm)

Soldering Method	Soldering Conditions	Recommended Soldering Symbols
Infrared reflow	Package peak temperature: 235 °C, Duration: 30 sec. max. (at 210 °C or above), Number of times: Three times max.	IR35-00-3
VPS	Package peak temperature: 215 °C, Duration: 40 sec. (at 200 °C or above), Number of times: Three times max.	VP15-00-3
Wave soldering	Solder bath temperature: 260 °C max., Duration: 10 sec. max., Number of times: Once, Preheating temperature: 120 °C max. (Package surface temperature)	WS60-00-1
Partial heating	Pin temperature: 300 °C max., Duration: 3 sec. max. (per device side)	—

★ (2) μPD780306YGC-xxx-8EU: 100-pin plastic LQFP (fine pitch) (14 × 14 mm)

μPD780308YGC-xxx-8EU: 100-pin plastic LQFP (fine pitch) (14 × 14 mm)

Soldering Method	Soldering Conditions	Recommended Soldering Symbols
Infrared reflow	Package peak temperature: 235 °C, Duration: 30 sec. max. (at 210 °C or above), Number of times: Twice max.	IR35-00-2
VPS	Package peak temperature: 215 °C, Duration: 40 sec. (at 200 °C or above), Number of times: Twice max.	VP15-00-2
Partial heating	Pin temperature: 300 °C max., Duration: 3 sec. max. (per device side)	—

Caution Use of more than one soldering method should be avoided (except in the case of partial heating).

★ APPENDIX A. DEVELOPMENT TOOLS

The following development tools are available for system development using μPD780306Y/780308Y.
 Also refer to (5) Notes on using development tools.

(1) Language Processing Software

RA78K/0	78K/0 series common assembler package
CC78K/0	78K/0 series common C compiler package
DF780308	Device file common to μPD780308 subseries (Part number : μSxxxxDF78064)
CC78K/0-L	78K/0 series common C compiler library source file

(2) PROM Writing Tools

PG-1500	PROM programmer
PA-78P0308GC PA-78P0308GF PA-78P0308KL-T	Programmer adapters connected to PG-1500
PG-1500 controller	PG-1500 control program

(3) Debugging Tools

- When in-circuit emulator IE-78K0-NS is used

IE-78K0-NS	In-circuit emulator common to 78K/0 series
IE-70000-MC-PS-B	Power supply unit for IE-78K0-NS
IE-70000-98-IF-C	Interface adapter used when PC-9800 series (except notebook type) is used as host machine
IE-70000-CD-IF	PC card and interface cable used when notebook type PC-9800 series is used as host machine
IE-70000-PC-IF-C	Interface adapter used when IBM PC/AT™ compatible machine is used as host machine
IE-780308-NS-EM1	Emulation board to emulate μPD780308 subseries
NP-100GC	Emulation probe for 100-pin plastic LQFP (GC-3EU type)
NP-100GF	Emulation probe for 100-pin plastic QFP (GF-3BA type)
TGC-100SDW	Conversion adapter to connect NP-100GC and a target system board made to be mounted on 100-pin plastic LQFP (GC-8EU type)
EV-9200GF-100	Socket to be mounted on a target system board made for 100-pin plastic QFP (GF-3BA type)
ID78K0-NS	Integrated debugger for IE-78K0-NS
SM78K0	78K/0 series common system simulator
DF780308	μPD780308 subseries device file (Part number: μSxxxxDF78064)

• When in-circuit emulator IE-78001-R-A is used

IE-78001-R-A	In-circuit emulator common to 78K/0 series
IE-70000-98-IF-B IE-70000-98-IF-C	Interface adapter used when PC-9800 series (except notebook type) is used as host machine
IE-70000-PC-IF-B IE-70000-PC-IF-C	Interface adapter used when IBM PC/AT compatible machine is used as host machine
IE-78000-R-SV3	Interface adapter and cable used when EWS is used as host machine
IE-780308-NS-EM1 IE-780308-R-EM	Emulation board to emulate μPD780308 subseries
IE-78K0-R-EX1	Emulation probe conversion board necessary when using IE-780308-NS-EM1 on IE-78001-R-A
NP-100GC	Emulation probe for 100-pin plastic LQFP (GC-3EU type)
NP-100GF	Emulation probe for 100-pin plastic QFP (GF-3BA type)
TGC-100SDW	Conversion adapter to connect NP-100GC and a target system board made to be mounted on 100-pin plastic LQFP (GC-8EU type)
EV-9200GF-100	Socket mounted on board of target system created for 100-pin plastic QFP (GF-3BA type)
ID78K0	Integrated debugger for IE-78001-R-A
SM78K0	System simulator common to 78K/0 series
DF780308	Device file for μPD780308 subseries (Part number: μSxxxxDF78064)

(4) Real-Time OS

RX78K/0	78K/0 series real-time OS
MX78K0	78K/0 series OS

(5) Notes on using development tools

- The package name of DF780308 is the DF78064.
- Use ID78K0-NS, ID78K0, and SM78K0 in combination with DF780308.
- Use CC78K/0 and RX78K/0 in combination with RA78K/0 and DF780308.
- NP-100GC and NP-100GF are products of Naito Densai Machida Mfg. Co., Ltd. (TEL (044) 822-3813). Consult your NEC distributor when purchasing these products.
- TGC-100SDW is a product of Tokyo Eletech Corp.
Reference: Daimaru Kogyo Ltd. Electronics Dept. (TEL: Tokyo 03-3820-7112)
Electronics 2nd Dept. (TEL: Osaka 06-244-6672)

- ★ • For development tools made by third parties, refer to **Single-chip Microcontroller Development Tool Selection Guide (U11069E)**.
- The host machine corresponding to each software package is as follows:

Host Machine [OS]	PC	EWS
	PC-9800 series [Windows™] IBM PC/AT Compatible Machines [Japanese/English Windows]	HP9000 series 700™ [HP-UX™] SPARCstation™ [SunOS™, Solaris™] NEWS (RISC)™ [NEWS-OS™]
Software		
RA78K/0	○Note	○
CC78K/0	○Note	○
PG-1500 controller	○Note	—
ID78K0-NS	○	—
ID78K0	○	○
SM78K0	○	—
RX78K/0	○Note	○
MX78K0	○Note	○

Note This software is based on DOS.

★ APPENDIX B. RELATED DOCUMENTS

Device Related Documents

Document Name		Document No.
μPD780308, 780308Y Subseries User's Manual		U11377E
μPD780306, 780308 Data Sheet		U11105E
μPD780306Y, 780308Y Data Sheet		This document
μPD78P0308 Data Sheet		U11776E
μPD78P0308Y Data Sheet		U11832E
78K/0 Series User's Manual (Instruction)		U12326E
78K/0 Series Application Note	Basic (III)	U10182E

Development Tool Related Documents (User's Manual) (1/2)

Document Name		Document No.
RA78K0 Assembler Package	Operation	U11802E
	Assembly language	U11801E
	Structured assembly language	U11789E
CC78K0 C Compiler	Operation	U11517E
	Language	U11518E
PG-1500 PROM Programmer		U11940E
IE-78K0-NS In-circuit Emulator		U13731E
IE-78K0-R-EX1 In-circuit Emulator		Planned
IE-780308-NS-EM1 Emulation Board		U13304E
IE-780308-R-EM Emulation Board		U11362E
EP-78064 Emulation Probe		EEU-1469

Caution The above related documents are subject to change without notice. For design purpose, etc., be sure to use the latest documents.

Development Tool Related Documents (User's Manual) (2/2)

Document Name		Document No.
SM78K0S, SM78K0 System Simulator Ver. 2.10 or later Windows Based	Operation	U14611E
SM78K Series System Simulator Ver. 2.10 or later	External part user open interface specifications	Planned
ID78K0-NS Integrated Debugger Ver. 2.00 or later Windows Based	Operation	U14379E
ID78K0-NS, ID78K0S-NS Integrated Debugger Ver. 2.20 or later Windows Based	Operation	U14910E
ID78K0 Integrated Debugger Windows Based	Reference	U11539E
	Guide	U11649E

Embedded Software Related Documents (User's Manual)

Document Name		Document No.
78K/0 Series Real-Time OS	Fundamentals	U11537E
	Installation	U11536E
78K/0 Series OS MX78K0	Fundamental	U12257E

Other Related Documents

Document Name		Document No.
SEMICONDUCTOR SELECTION GUIDE Products & Packages (CD-ROM)		X13769X
Semiconductor Device Mounting Technology Manual		C10535E
Quality Grades on Semiconductor Devices		C11531E
NEC Semiconductor Device Reliability and Quality Control		C10983E
Guide to Prevent Damage for Semiconductor Devices by Electrostatic Discharge (ESD)		C11892E

Caution The above related documents are subject to change without notice. For design purpose, etc., be sure to use the latest documents.

[MEMO]

[MEMO]

NOTES FOR CMOS DEVICES**① PRECAUTION AGAINST ESD FOR SEMICONDUCTORS**

Note:

Strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred. Environmental control must be adequate. When it is dry, humidifier should be used. It is recommended to avoid using insulators that easily build static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work bench and floor should be grounded. The operator should be grounded using wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with semiconductor devices on it.

② HANDLING OF UNUSED INPUT PINS FOR CMOS

Note:

No connection for CMOS device inputs can be cause of malfunction. If no connection is provided to the input pins, it is possible that an internal input level may be generated due to noise, etc., hence causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using a pull-up or pull-down circuitry. Each unused pin should be connected to V_{DD} or GND with a resistor, if it is considered to have a possibility of being an output pin. All handling related to the unused pins must be judged device by device and related specifications governing the devices.

③ STATUS BEFORE INITIALIZATION OF MOS DEVICES

Note:

Power-on does not necessarily define initial status of MOS device. Production process of MOS does not define the initial operation status of the device. Immediately after the power source is turned ON, the devices with reset function have not yet been initialized. Hence, power-on does not guarantee out-pin levels, I/O settings or contents of registers. Device is not initialized until the reset signal is received. Reset operation must be executed immediately after power-on for devices having reset function.

Regional Information

Some information contained in this document may vary from country to country. Before using any NEC product in your application, please contact the NEC office in your country to obtain a list of authorized representatives and distributors. They will verify:

- Device availability
- Ordering information
- Product release schedule
- Availability of related technical literature
- Development environment specifications (for example, specifications for third-party tools and components, host computers, power plugs, AC supply voltages, and so forth)
- Network requirements

In addition, trademarks, registered trademarks, export restrictions, and other legal issues may also vary from country to country.

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